



Beam Diagnostics

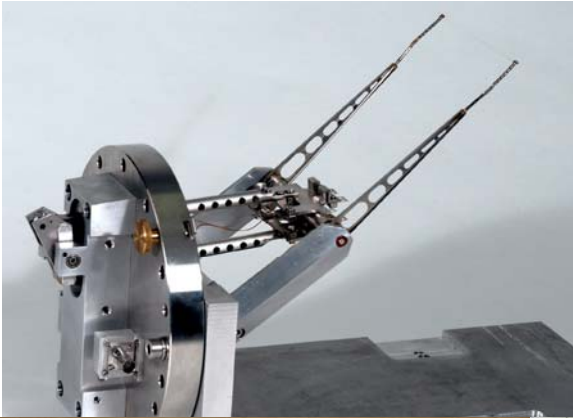
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(Beam Diagnostics and Instrumentation)

Introduction

An accelerator can never be better than the instruments measuring its performance!





Course Overview

- Generalities
- Intensity measurements
 - Faraday Cup
 - AC current transformer
 - DC current transformer
- Profile measurements
 - TV screens
 - SEMgrids
 - Wire scanners
- Emittance
 - Phase space scans
 - Pepperpot
- Position measurements



Different uses of beam diagnostics

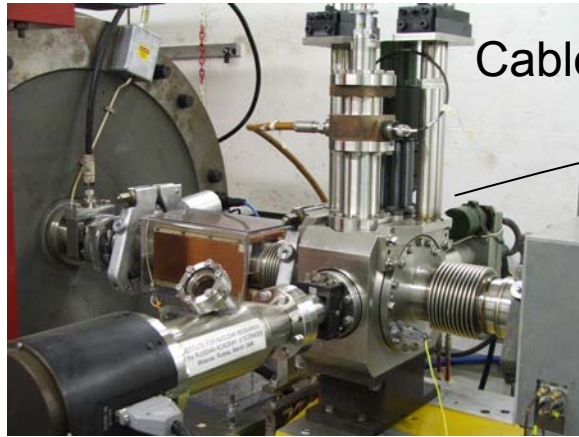
- **Regular crude checks of accelerator performance**
 - Beam Intensity
 - Radiation levels
- **Standard regular measurements**
 - Emittance measurement
 - Trajectories
 - Tune
- **Sophisticated measurements e.g. during machine development sessions**
 - May require offline evaluation
 - May be less *comfortable*



Diagnostic devices and quantity measured

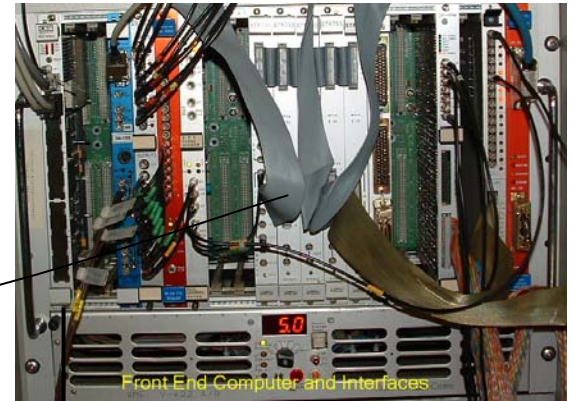
Instrument	Physical Effect	Measured Quantity	Effect on beam
Faraday Cup	Charge collection	Intensity	Destructive
Current Transformer	Magnetic field	Intensity	Non destructive
Wall current monitor	Image Current	Intensity Longitudinal beam shape	Non destructive
Pick-up	Electric/magnetic field	Position	Non destructive
Secondary emission monitor	Secondary electron emission	Transverse size/shape, emittance	Disturbing, can be destructive at low energies
Wire Scanner	Secondary particle creation	Transverse size/shape	Slightly disturbing
Scintillator screen	Atomic excitation with light emission	Transverse size/shape (position)	Destructive
Residual Gas monitor	Ionization	Transverse size/shape	Non destructive

Intensity measurements Faraday Cups



Sensor + amplifier/shaper

Cable from ring to equipment room



Computer network



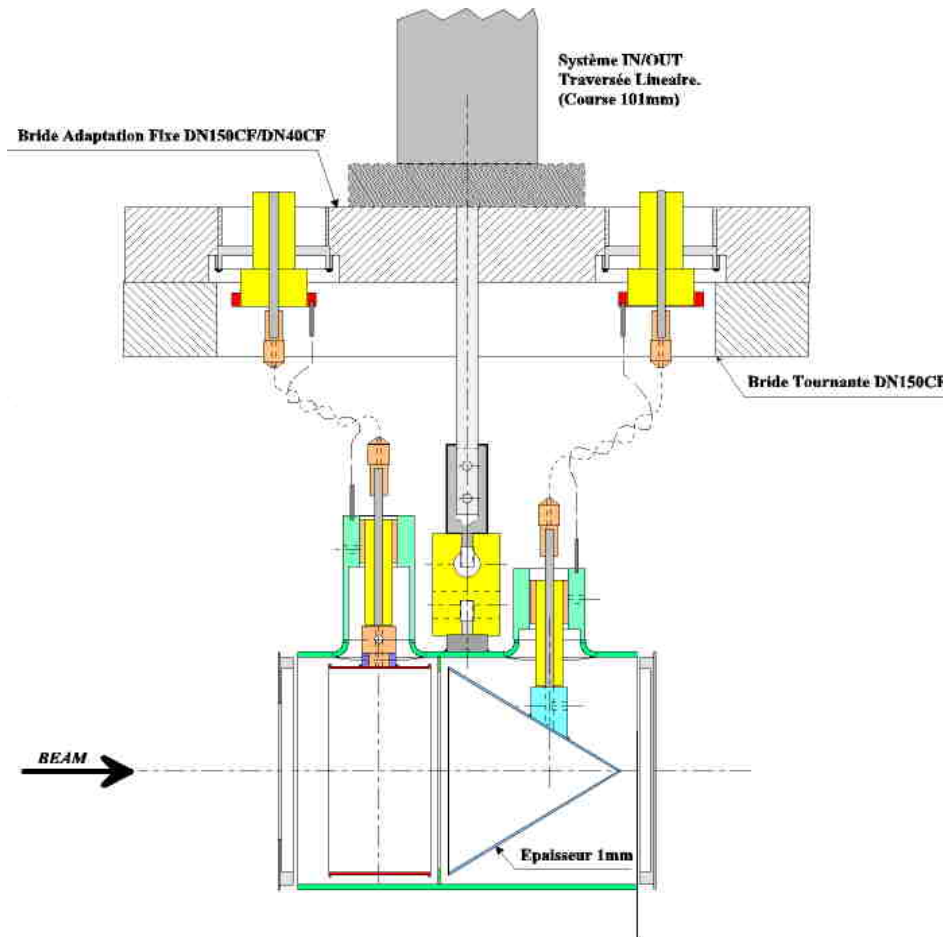


Required Competence in a beam diagnostics group

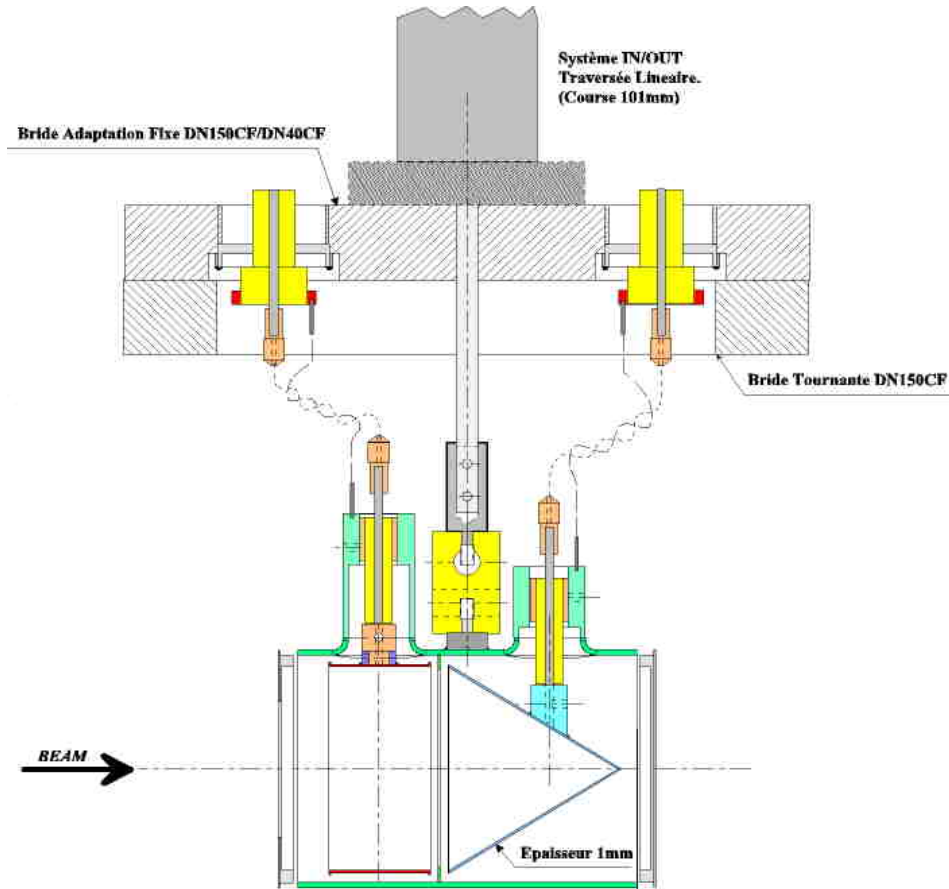
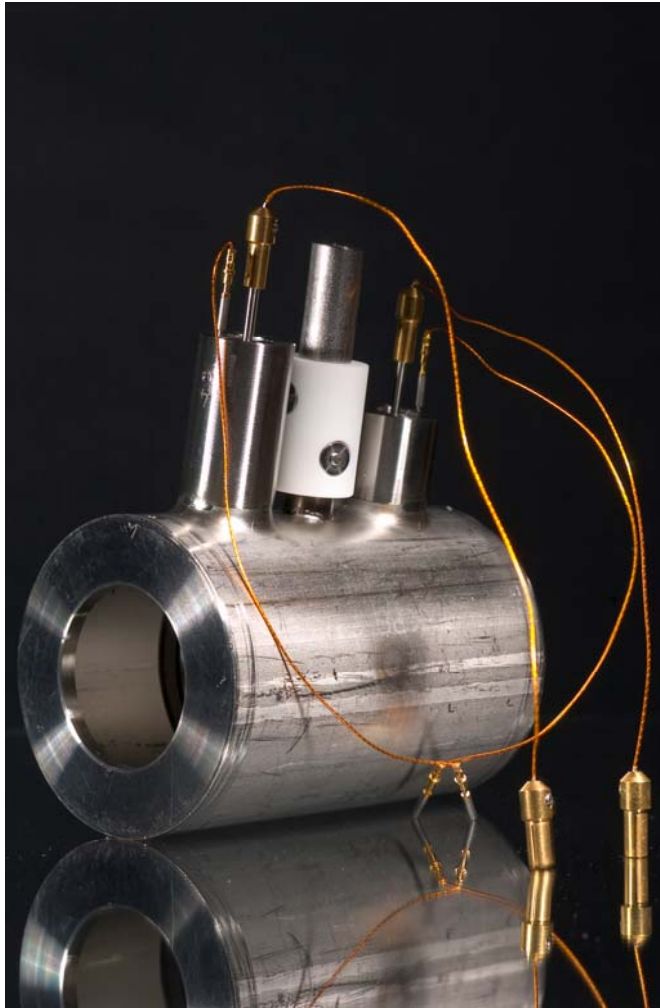
- Some beam physics in order to understand the beam parameters to be measured and to distinguish beam effects from sensor effects
- Detector physics to understand the interaction of the beam with the sensor
- Mechanics
- Analogue signal treatment
 - Low noise amplifiers
 - High frequency analogue electronics
- Digital signal processing
- Digital electronics for data readout
- Front-end and Application Software

Layout of a Faraday Cup

- Electrode: 1 mm stainless steel
- Only low energy particles can be measured
- Very low intensities (down to 1 pA) can be measured
- Creation of secondary electrons of low energy (below 20 eV)
- Repelling electrode with some 100 V polarisation voltage pushes secondary electrons back onto the electrode



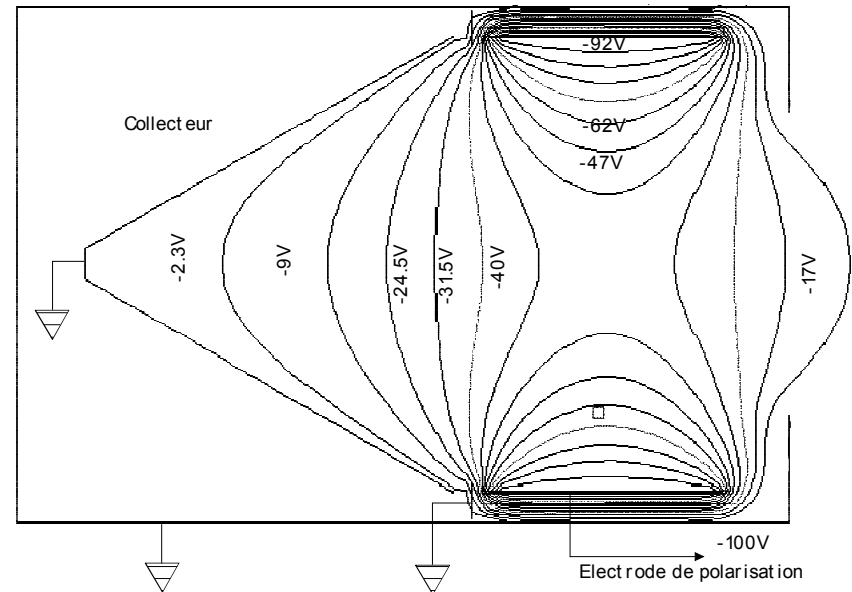
Faraday Cup



Electro-static Field in Faraday Cup

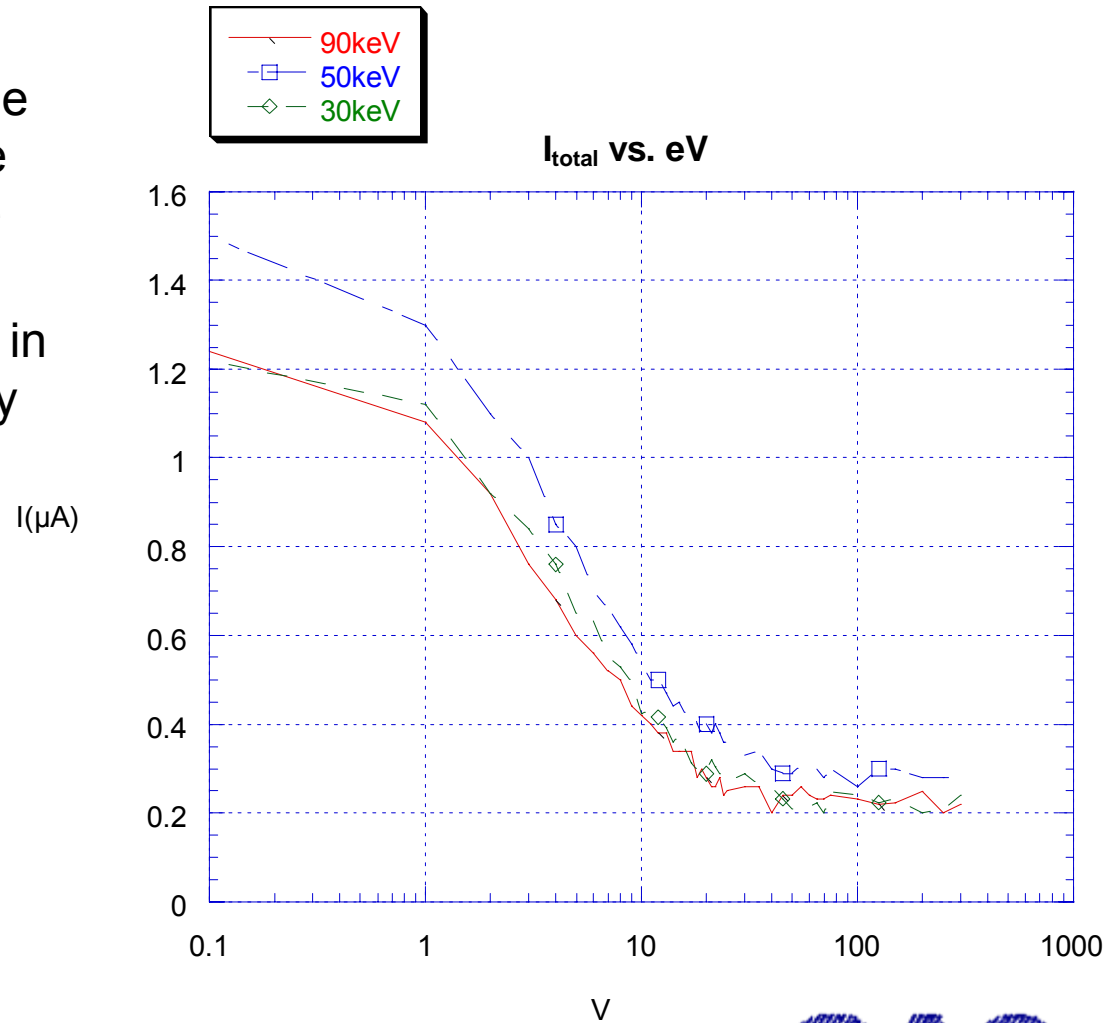
In order to keep secondary electrons with the cup a repelling voltage is applied to the polarization electrode

Since the electrons have energies of less than 20 eV some 100V repelling voltage is sufficient



Energy of secondary emission electrons

- With increasing repelling voltage the electrons do not escape the Faraday Cup any more and the current measured stays stable.
- At 40V and above no decrease in the Cup current is observed any more





Faraday Cup application

Testing the decelerating RFQ

Antiproton decelerator

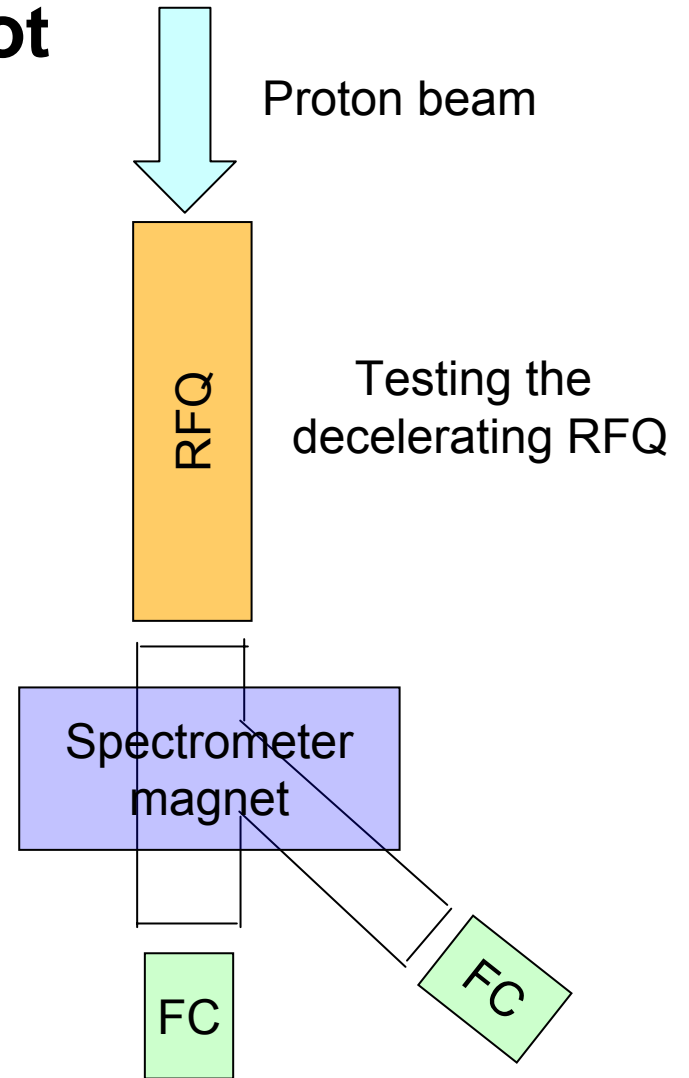
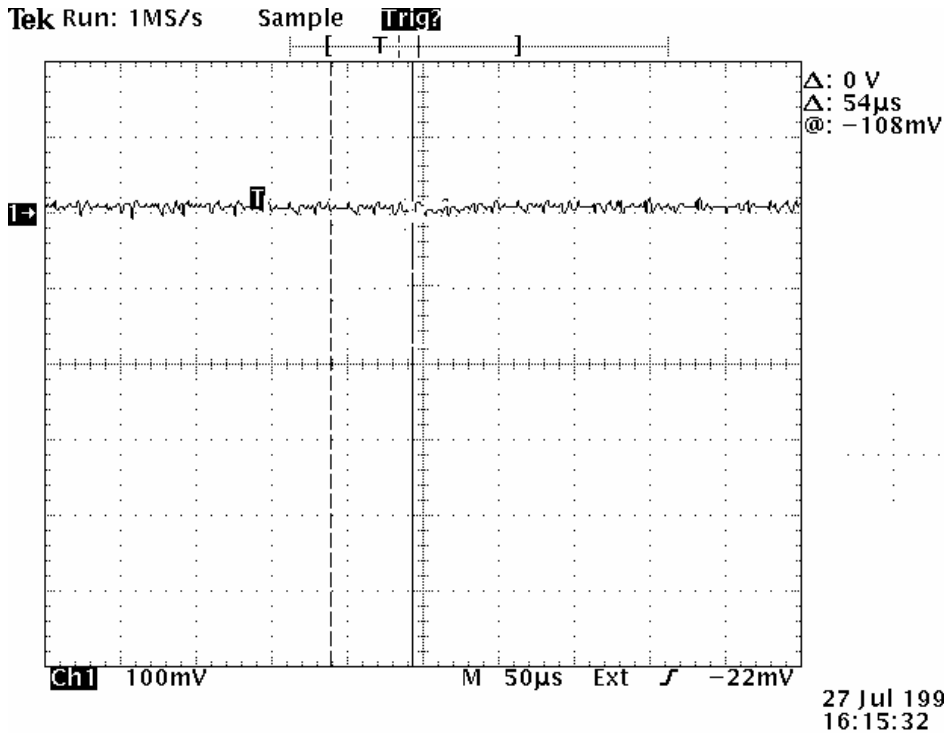
- Accelerate protons to 24 GeV and eject them onto a target
- Produce antiprotons at 2 GeV
- Collect the antiprotons and cool them
- Decelerate them and cool them
- Output energy: 100 MeV

In order to get even lower energies:

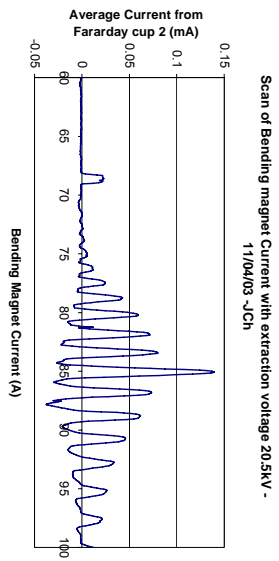
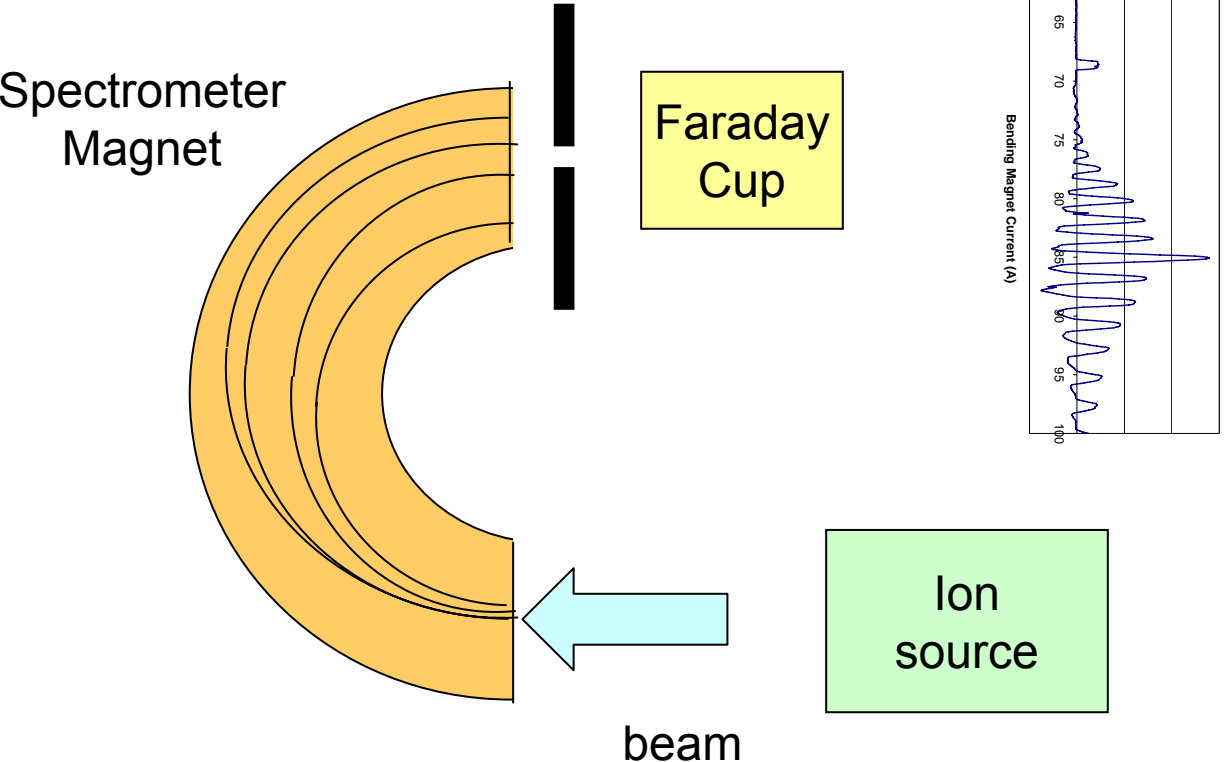
- Pass them through a moderator
 - High losses
 - Large energy distribution

=> **Build a decelerating RFQ**

Waiting for Godot

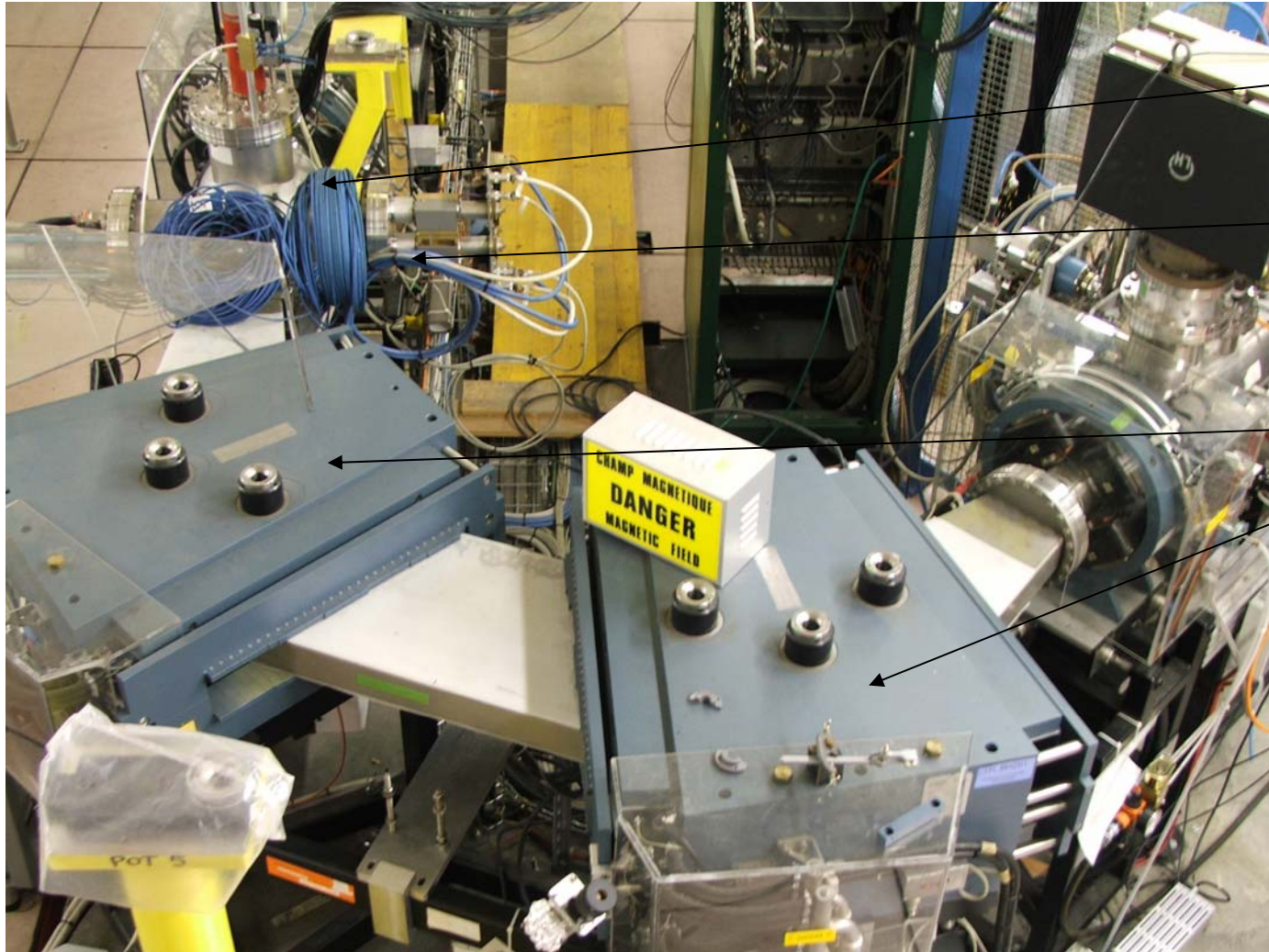


Setup for charge state measurement



The spectrometer magnet is swept and the current passing the slit is measured

Measuring charge state distribution



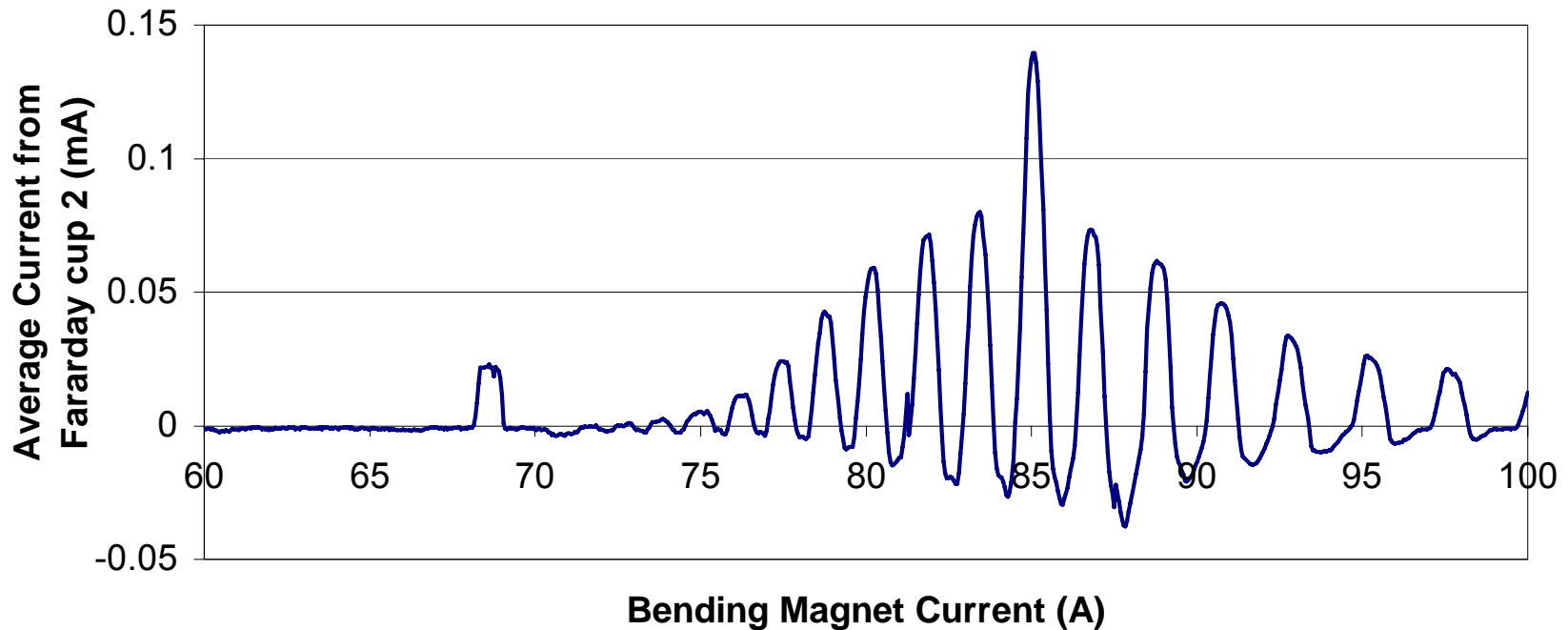
Faraday Cup

Slit

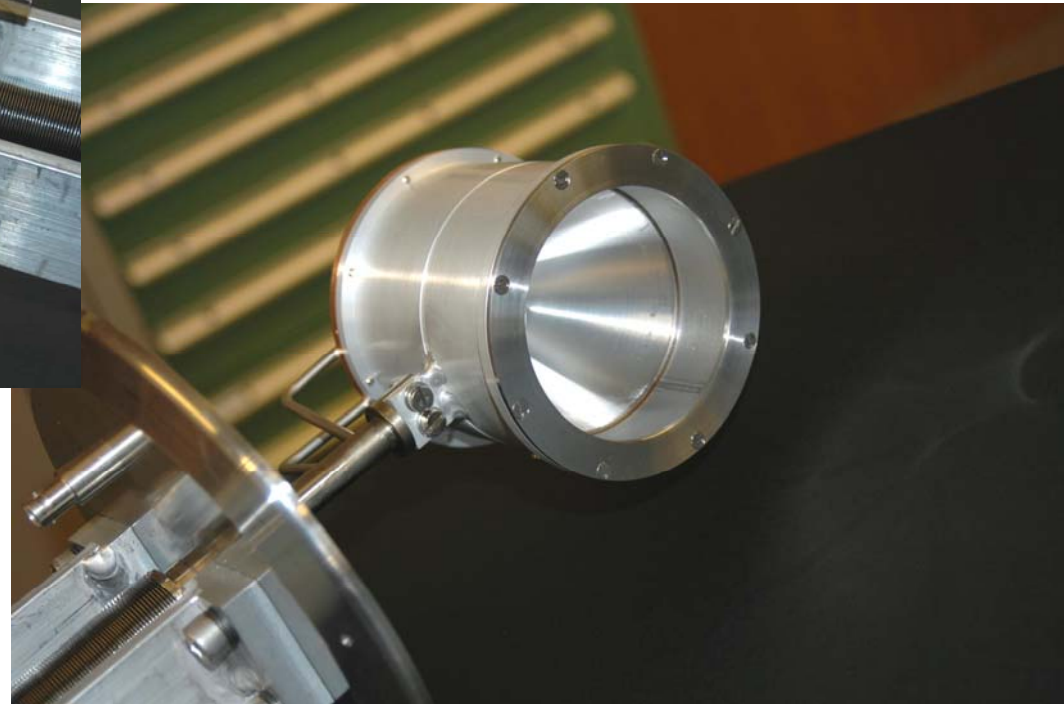
Spectrometer magnets

Charge state distribution measured with a Faraday Cup on a heavy ion source

Scan of Bending magnet Current with extraction voltage 20.5kV -
11/04/03 -JCh

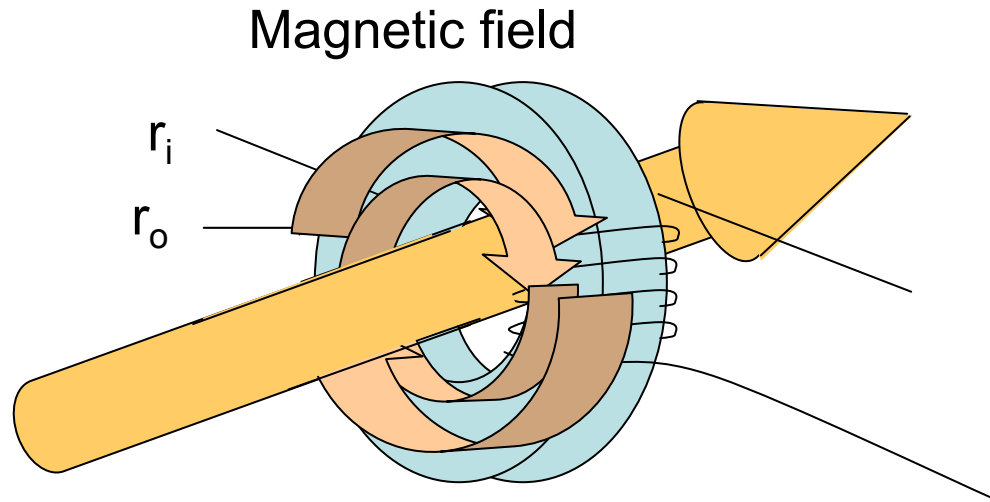


Faraday Cup with water cooling



For higher intensities
water cooling may be needed

Current Transformers



Fields are very low

Capture magnetic field lines with cores of high relative permeability

(CoFe based amorphous alloy Vitrovac: $\mu_r = 10^5$)

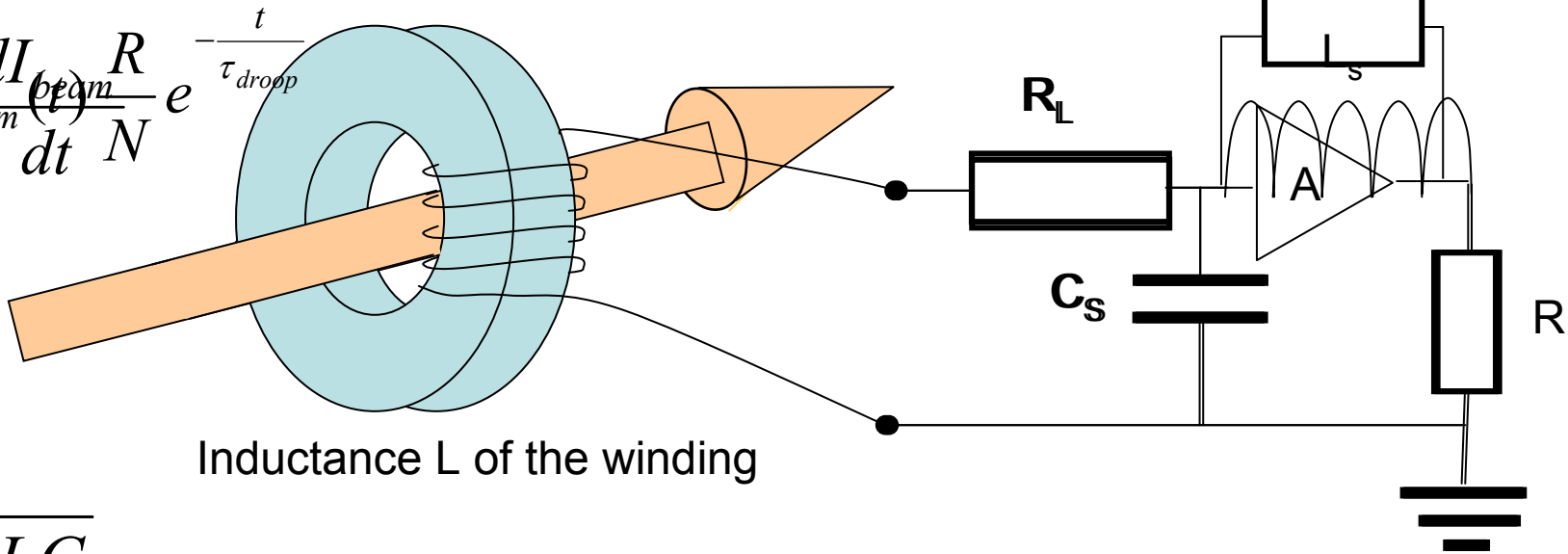
Beam current

$$I_{\text{beam}} = \frac{qeN}{t} = \frac{qeN\beta c}{l}$$

$$L = \frac{\mu_0 \mu_r}{2\pi} l N^2 \ln \frac{r_o}{r_i}$$

The Ideal Transformer

$$U(t) \equiv I_{beam} \frac{dI_{beam}}{dt} \frac{R}{N} e^{-\frac{t}{\tau_{drop}}}$$

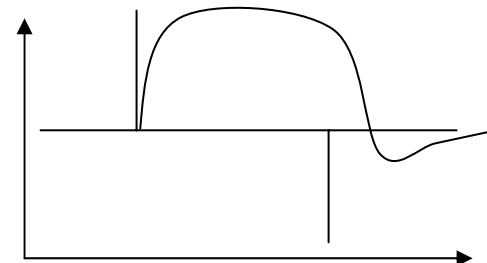
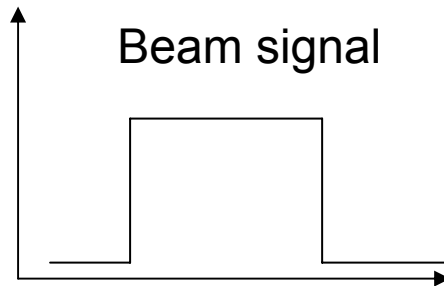


Inductance L of the winding

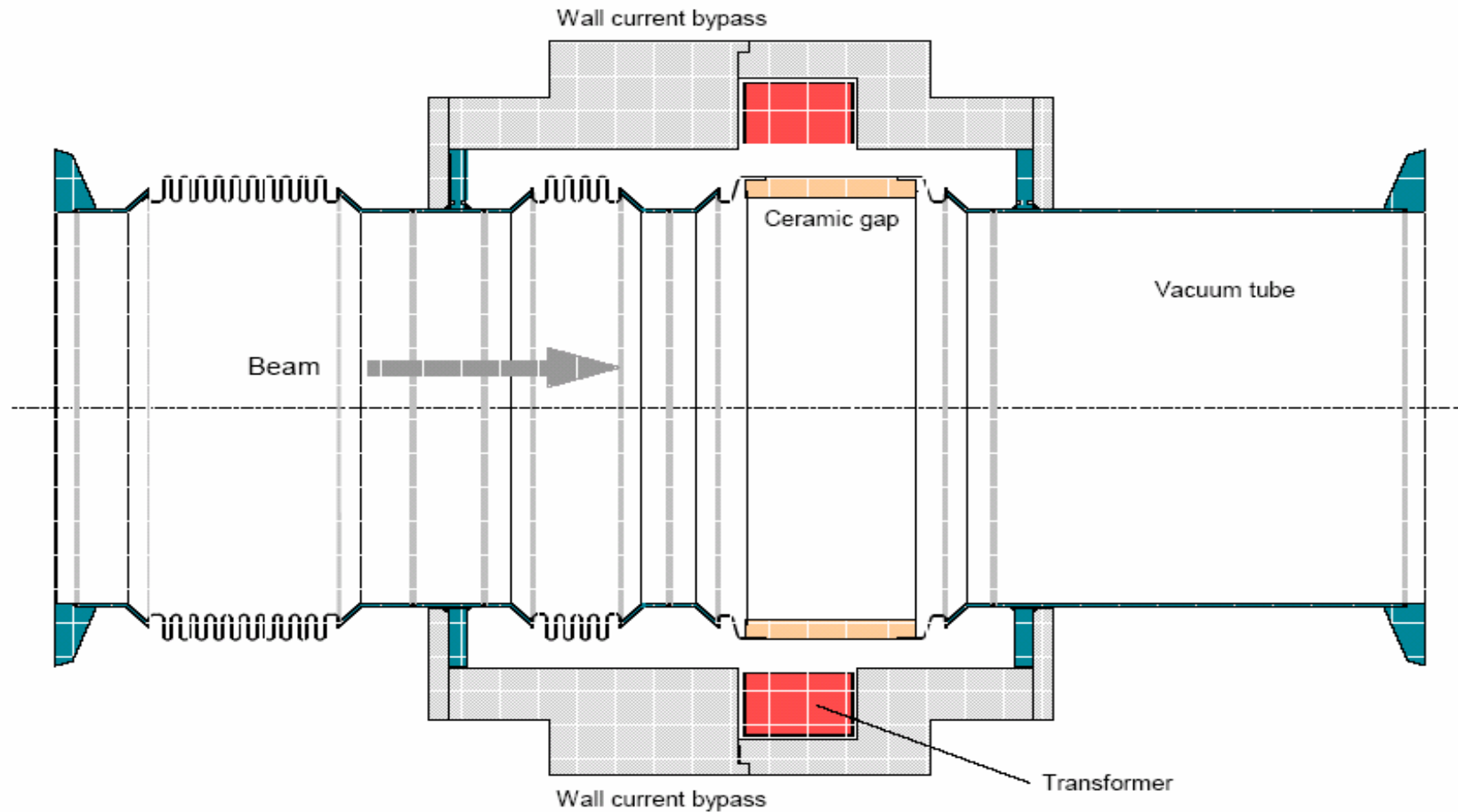
$$\tau_{rise} = \sqrt{L_s C_s}$$

$$\tau_{drop} = \frac{L_L}{\frac{R}{A} + R_L} \approx \frac{L}{R_L}$$

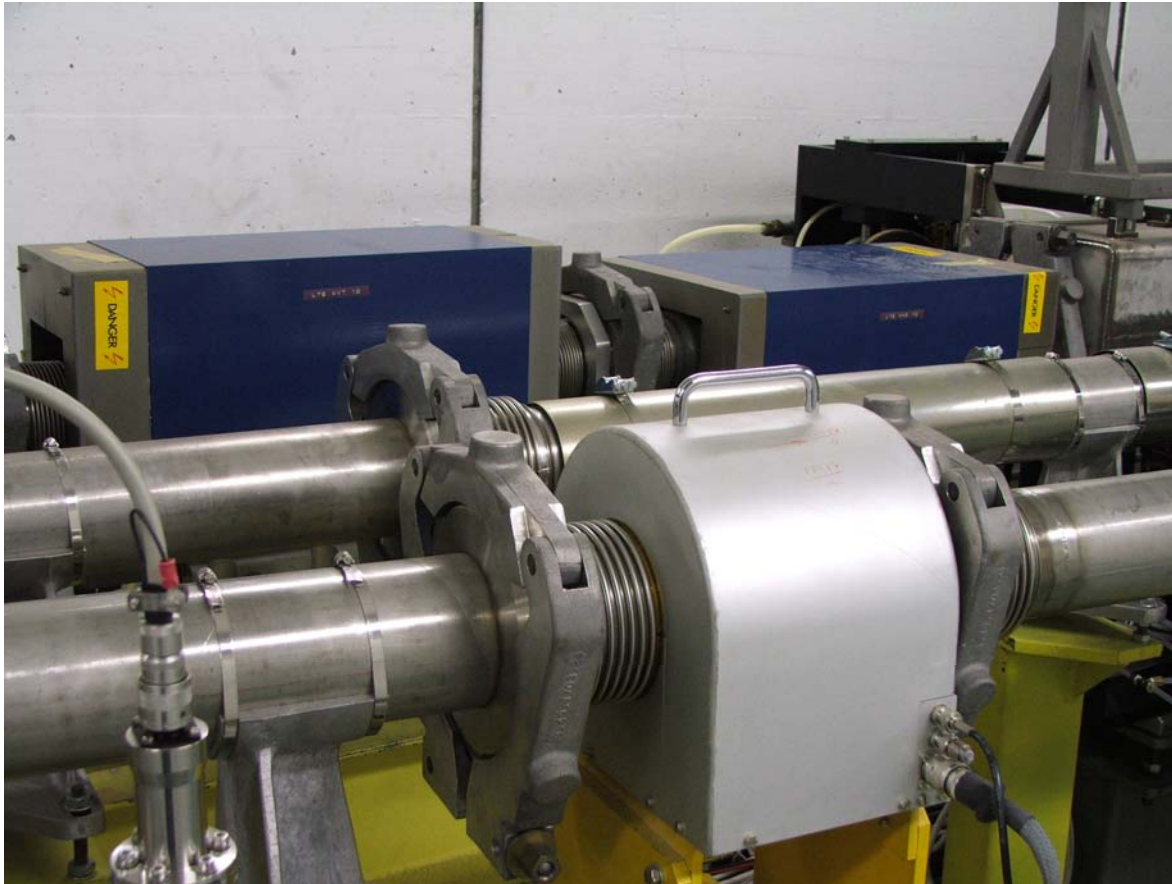
Transformer output signal



Principle of a fast current transformer



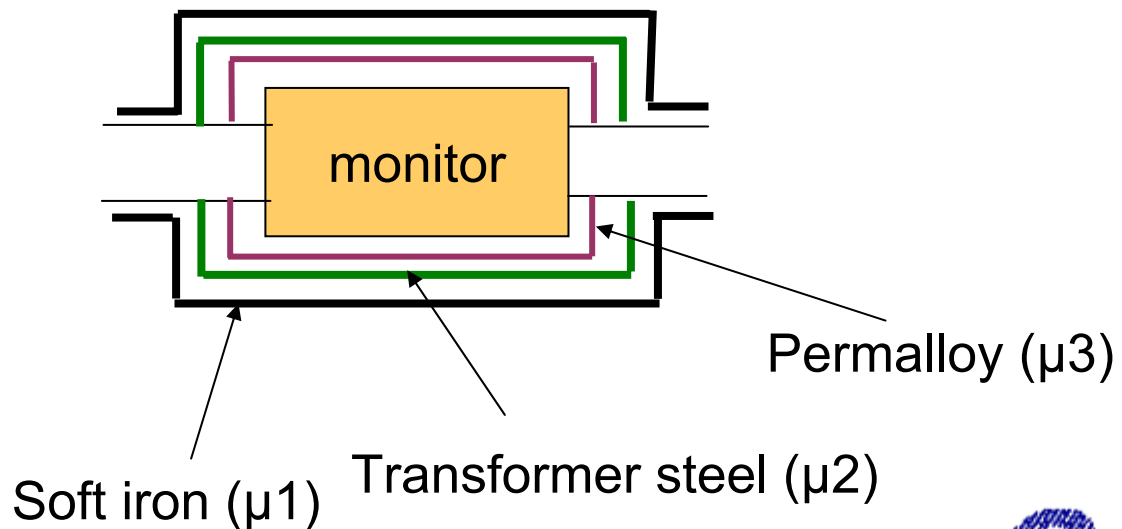
The transformer installed in the machine



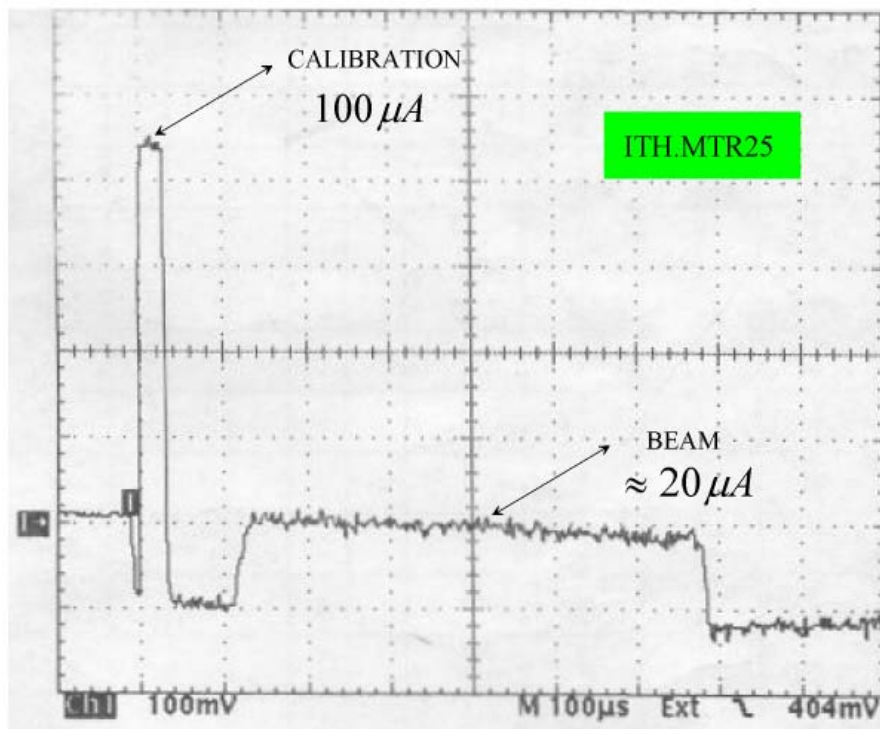
Needs
Magnetic Shielding

Magnetic shielding

- Shield should extend along the vacuum chamber length $>$ diameter of opening
- Shield should be symmetrical to the beam axis
- Air gaps must be avoided especially along the beam axis
- Shield should have highest μ possible but should not saturate



Calibration of AC current transformers



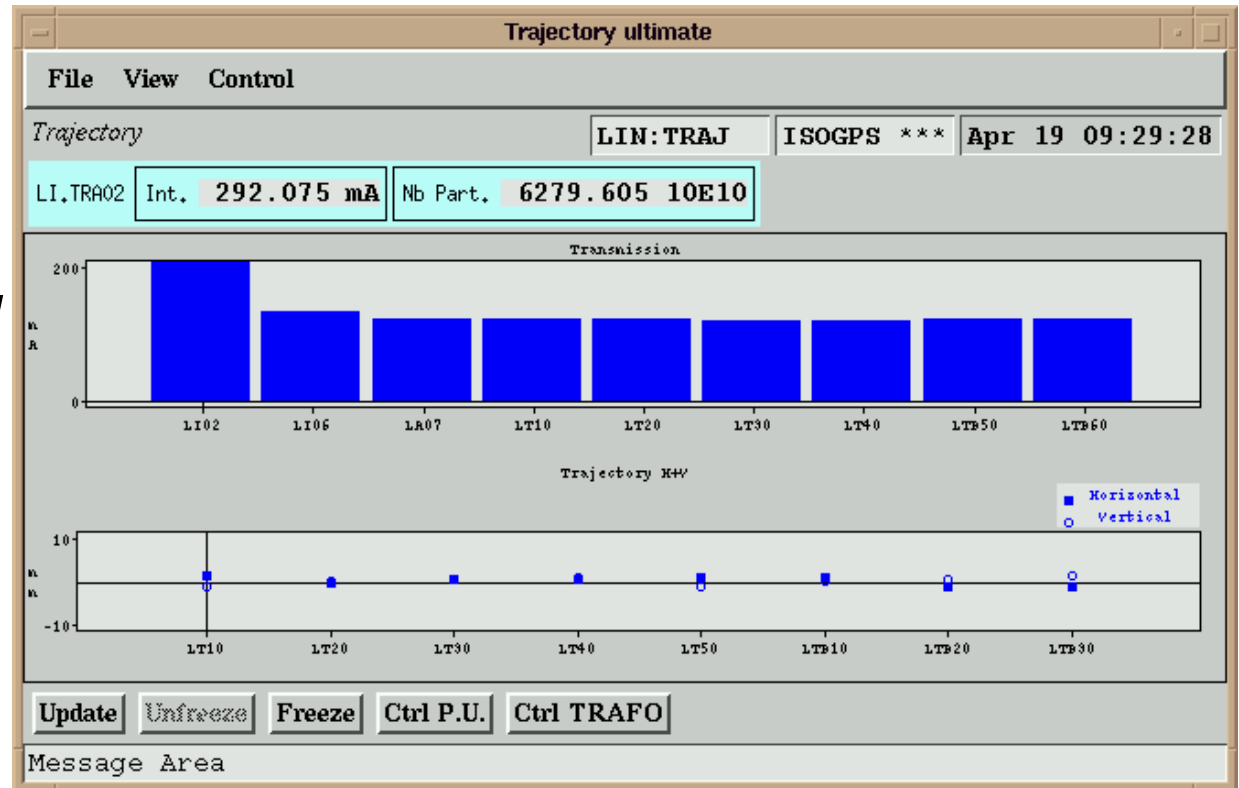
- The transformer is calibrated with a very precise current source
- The calibration signal is injected into a separate calibration winding
- A calibration procedure executed before the running period
- A calibration pulse before the beam pulse measured with the beam signal

Current transformer and its electronics



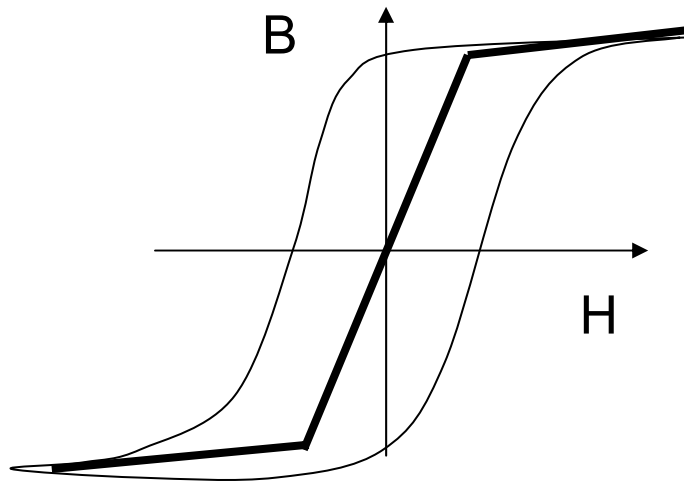
Display of transformer readings

- Transformers in a transfer line
- Calculated losses trigger a *watchdog*
- Display distributed via video signal

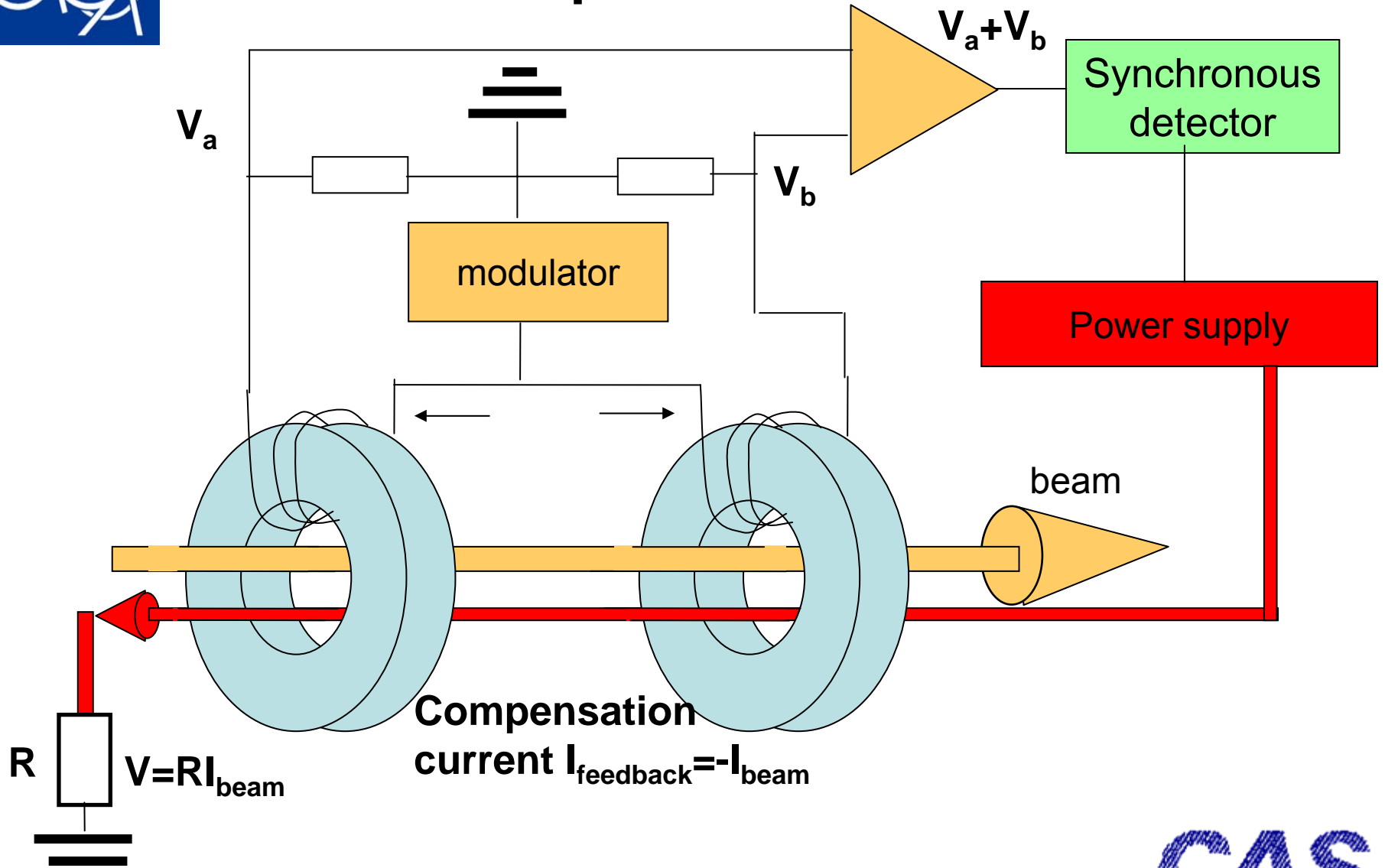


The DC current transformer

- AC current transformer can be extended to very long droop times but not to DC
- Measuring DC currents is needed in storage rings
- Must provide a modulation frequency
- Takes advantage of non/linear magnetisation curve



Principle of DCCT

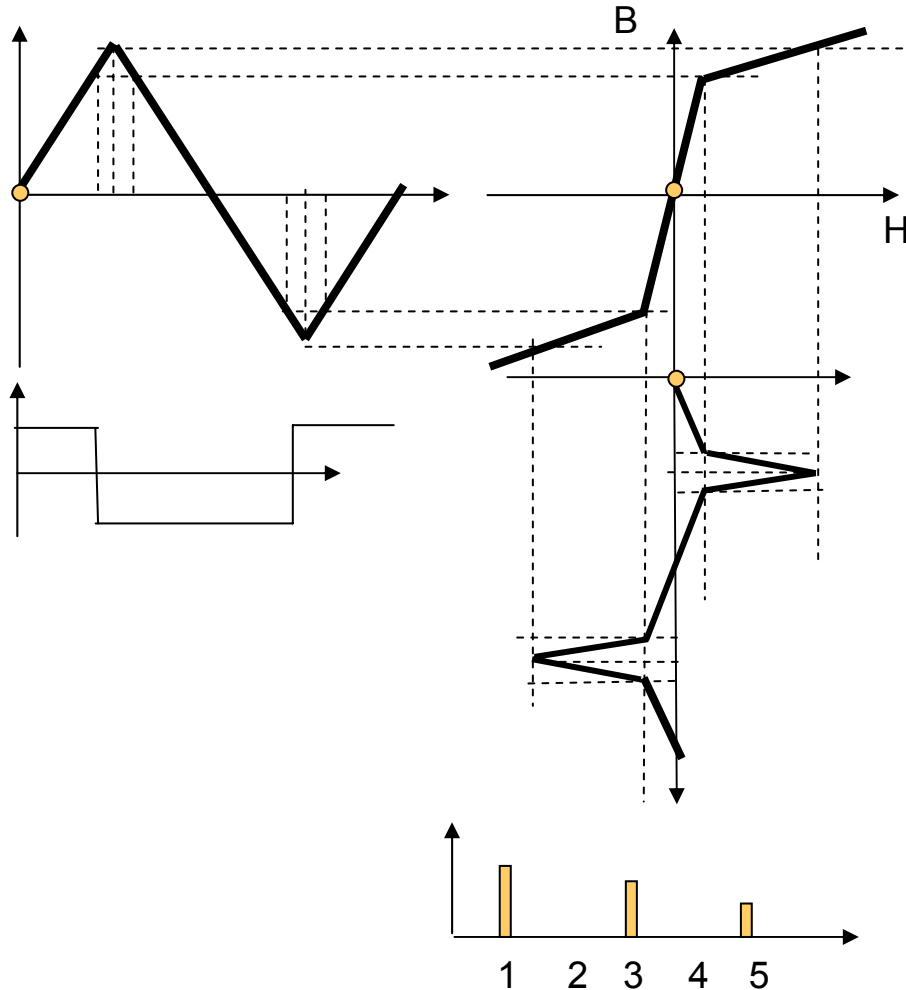


R $V = RI_{\text{beam}}$

Compensation current $I_{\text{feedback}} = -I_{\text{beam}}$

Modulation of a DCCT without beam

$$B=f(t)$$

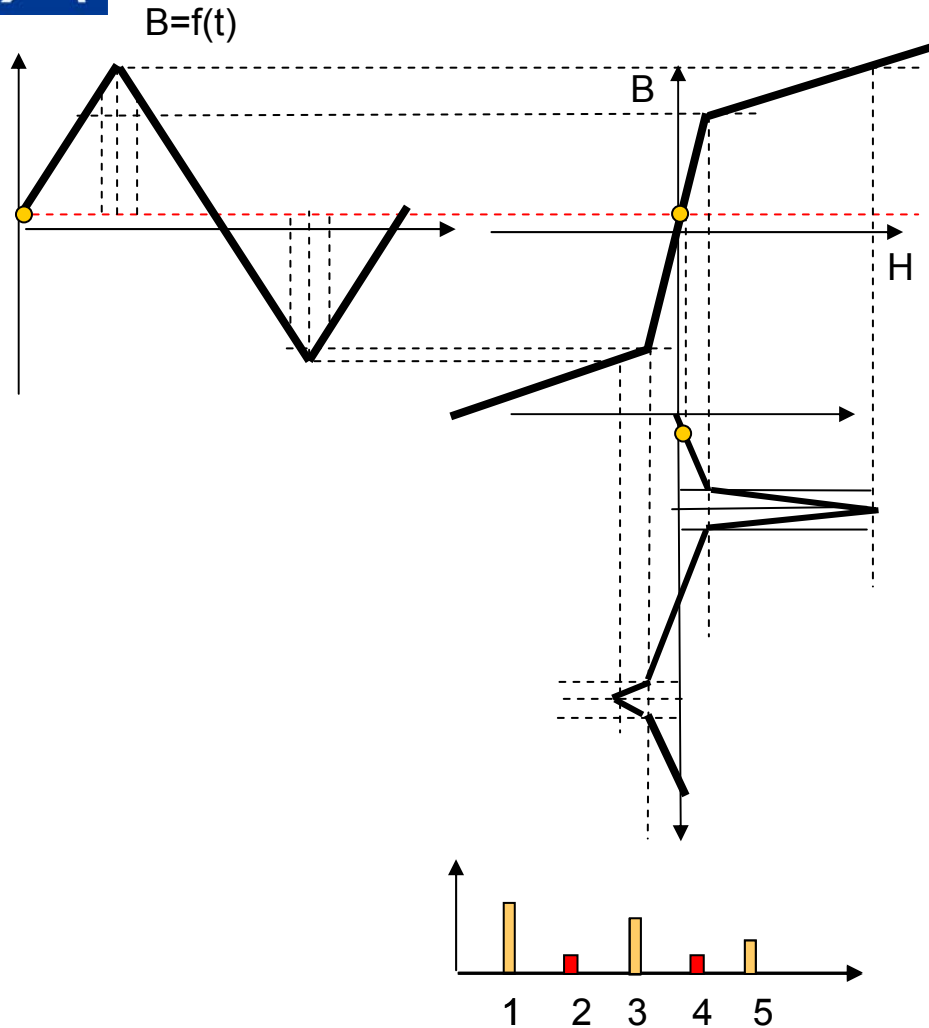


$$U = NA \frac{dB}{dt}$$

$$B = \frac{\int U dt}{NA} + B_0$$

Modulation current has only odd harmonic frequencies since the signal is symmetric

Modulation of a DCCT with beam



Sum signal becomes non-zero
Even harmonics appear

Modulation current difference signal with beam

- Difference signal has $2\omega_m$
- ω_m typically 200 Hz – 10 kHz
- Use low pass filter with $\omega_c \ll \omega_m$
- Provide a 3rd core, normal AC transformer to extend to higher frequencies

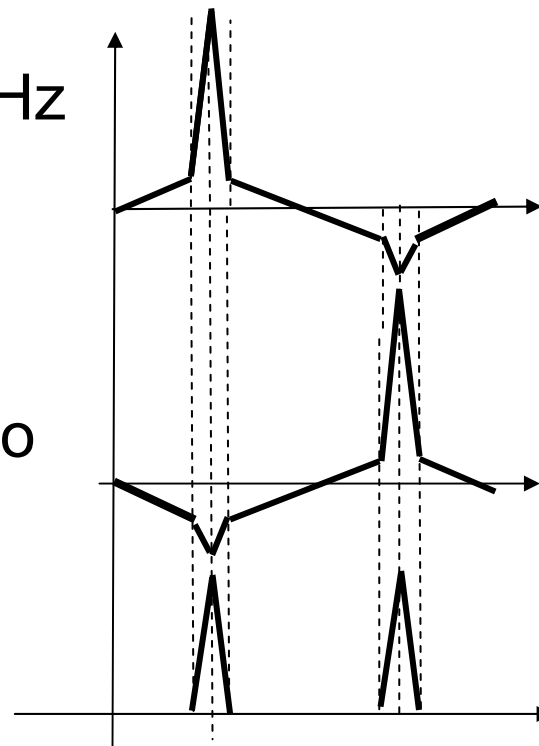
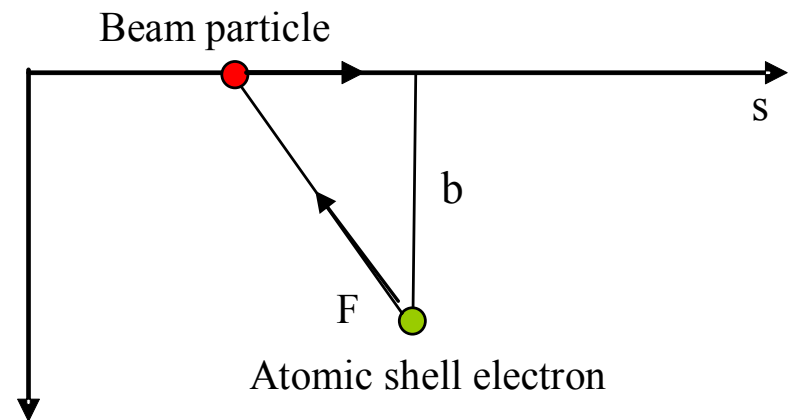


Photo of DCCT internals



Interaction of particles with matter

- Coulomb interaction
- Average force in s-direction=0
- Average force in transverse direction $\langle \rangle 0$
- Mostly large impact parameter \Rightarrow low energy of ejected electron
- Electron mostly ejection transversely to the particle motion



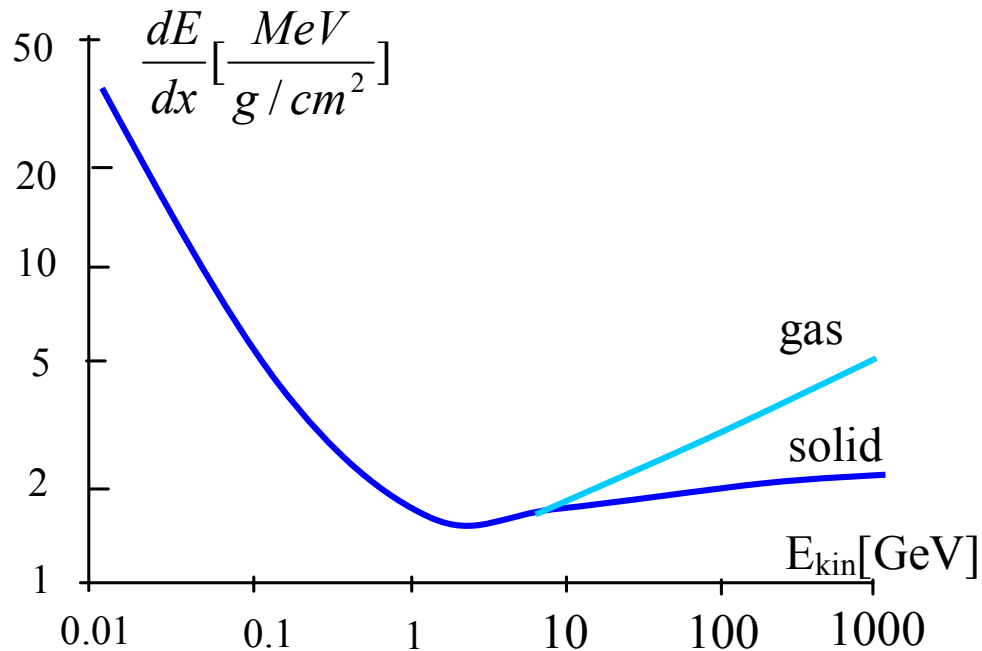
Bethe Bloch formula

$$-\frac{dE}{dx} = 4\pi N_A r_e^2 m_e c^2 \frac{Z_T}{A_T} \rho \frac{Z_p^2}{\beta^2} \left[\ln \frac{2m_e c^2 \gamma^2 \beta^2}{I} - \beta^2 \right]$$

- with the following constants:
 - NA: Avogadro's number
 - m_e and r_e : electron rest mass and classical electron radius
 - c: speed of light
- the following target material properties:
 - ρ : material density
 - A_T and Z_T : the atomic mass and nuclear charge
- and the particle properties:
 - Z_p : particle charge
 - β : the particle velocity and $\gamma = \sqrt{1 - \beta^2}$

Dependance on Z_p^2

High energy loss a low energies



Heavy ions at low energy are stopped within a few micro-meters
 All energy is deposited in a very small volume

Scintillating Screens

Method already applied in cosmic ray experiments

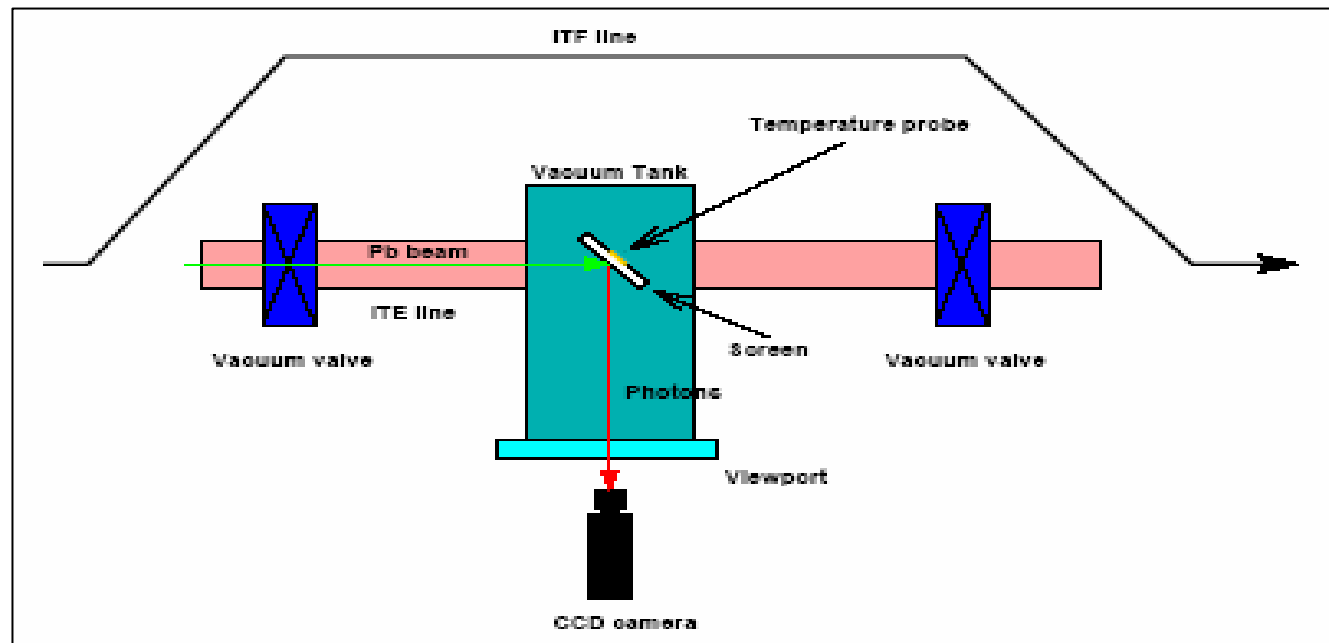
- Very simple
- Very convincing

Needed:

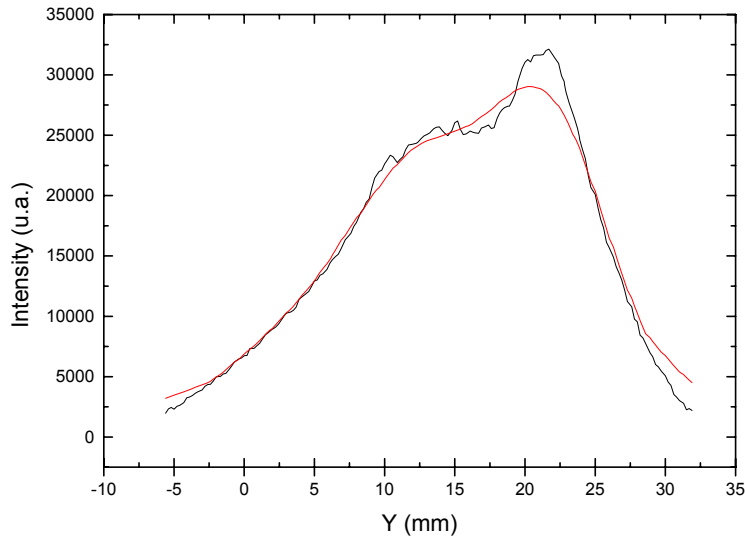
- Scintillating Material
- TV camera
- In/out mechanism

Problems:

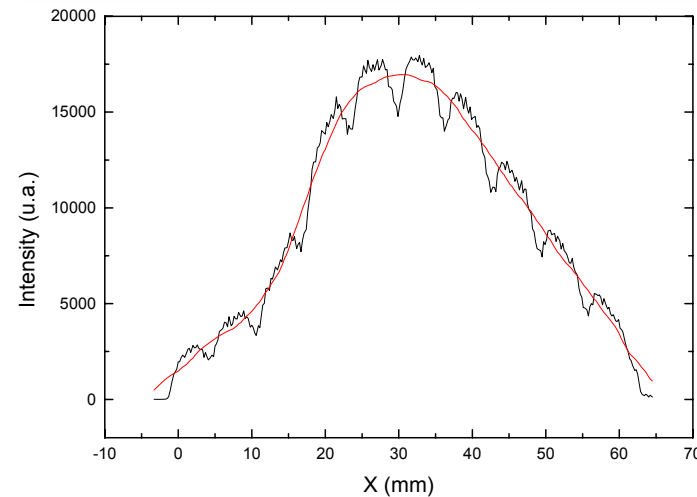
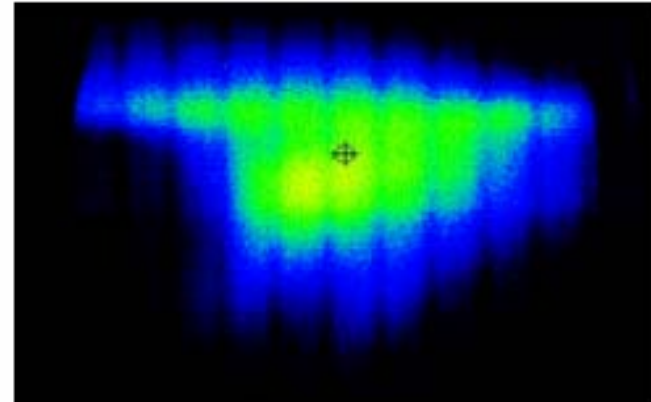
- Radiation resistance
- Heating of screen (absorption of beam energy)
- Evacuation of electric charges



Frame grabber



- For further evaluation the video signal is digitized, read-out and treated by program

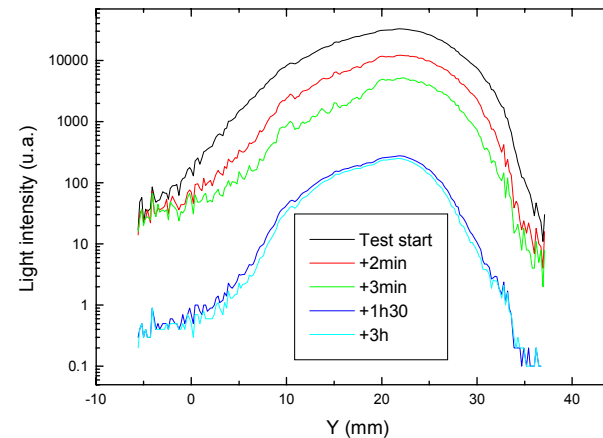
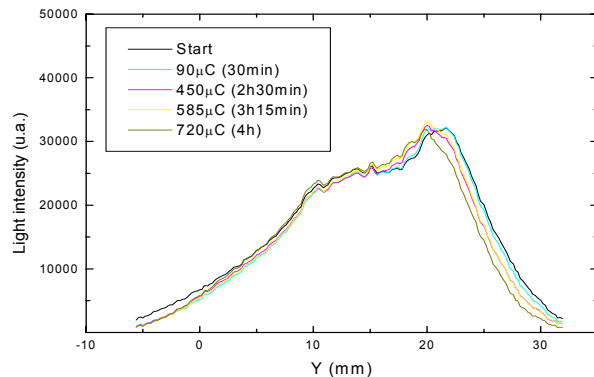


Test for resistance against heat-shock

Material	ρ <i>g/cm³</i>	c_p at 20°C <i>J/gK</i>	k at 100°C <i>W/mK</i>	T_{max} <i>°C</i>	R at 400°C <i>Ω.cm</i>
Al ₂ O ₃	3.9	0.9	30	1600	10 ¹²
ZrO ₂	6	0.4	2	1200	10 ³
BN	2	1.6	35	2400	10 ¹⁴

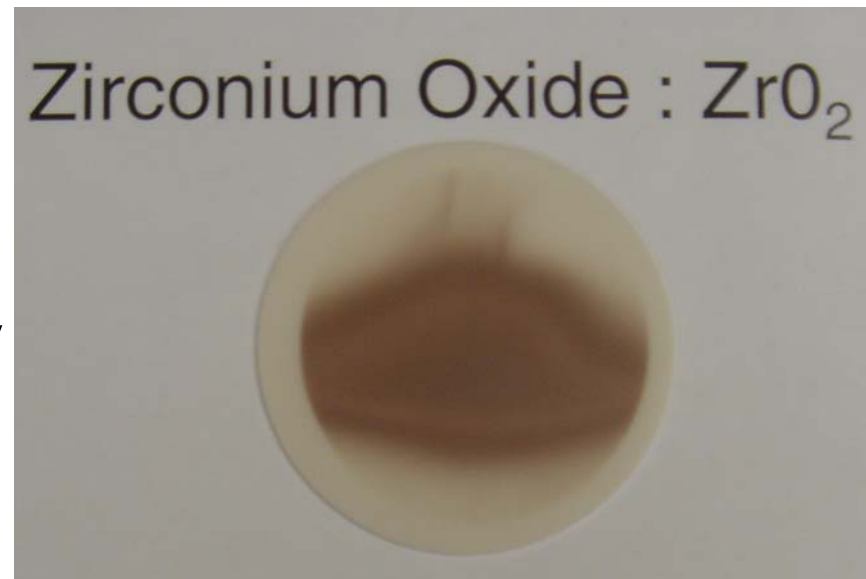
Better for electrical conductivity (>400°C)

Better for thermal properties
(higher conductivity, higher heat capacity)



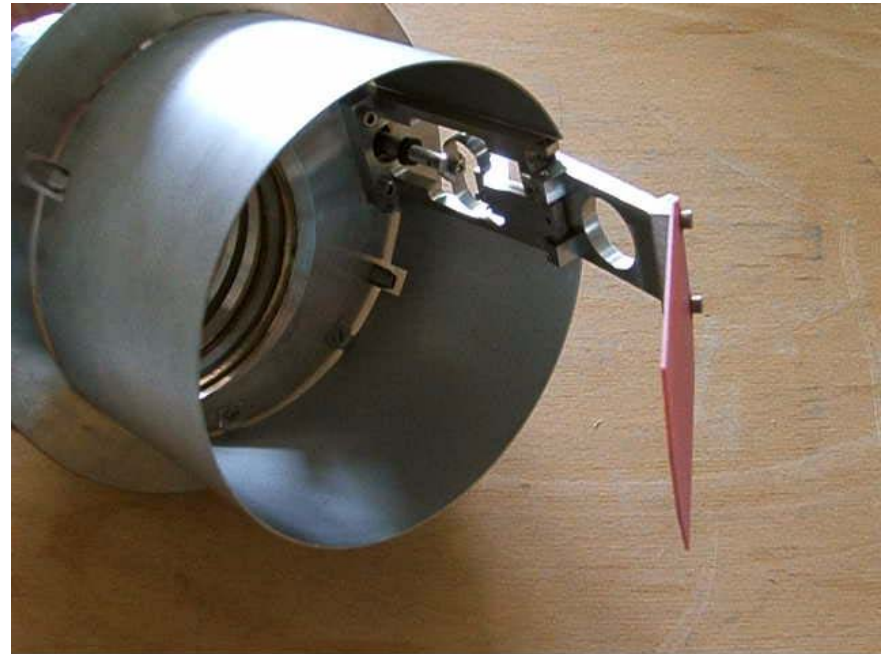
Degradation of screen

Degradation clearly visible
However sensitivity stays essentially
the same



Screen mechanism

- Screen with graticule

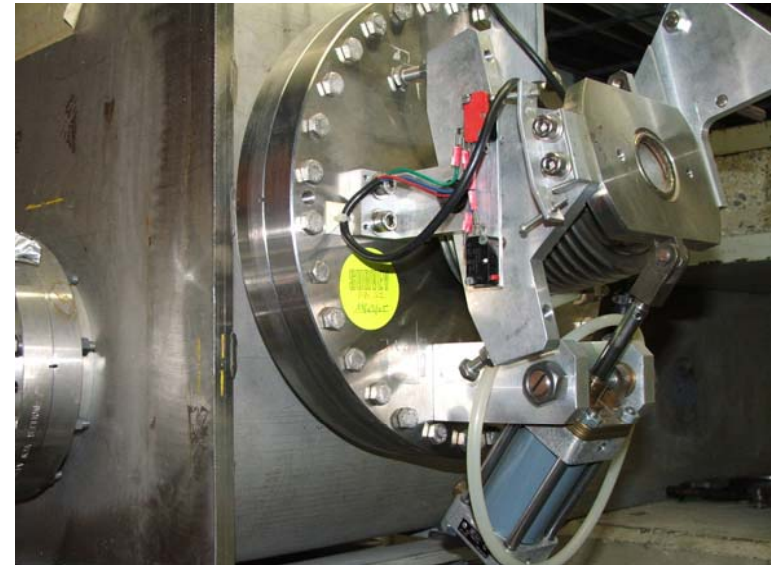


In/out mechanisms

Rotary mechanism driven by electric motor



Mechanism driven pneumatically



Profile measurements

- Secondary emission grids (SEMgrids)

When the beam passes secondary electrons are ejected from the ribbons

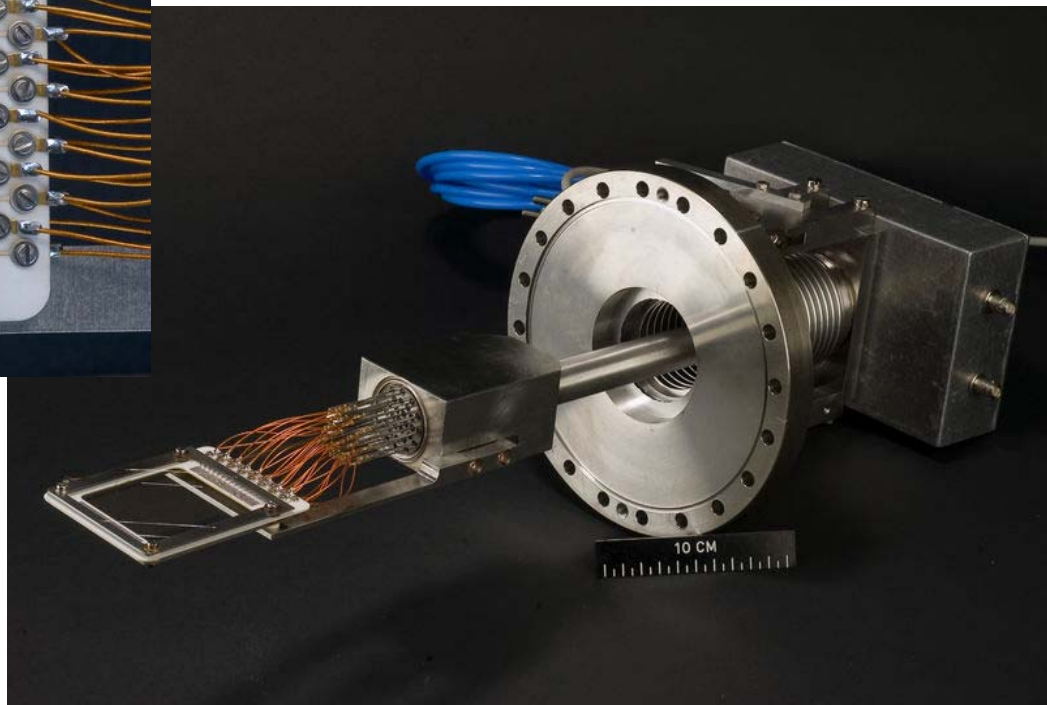
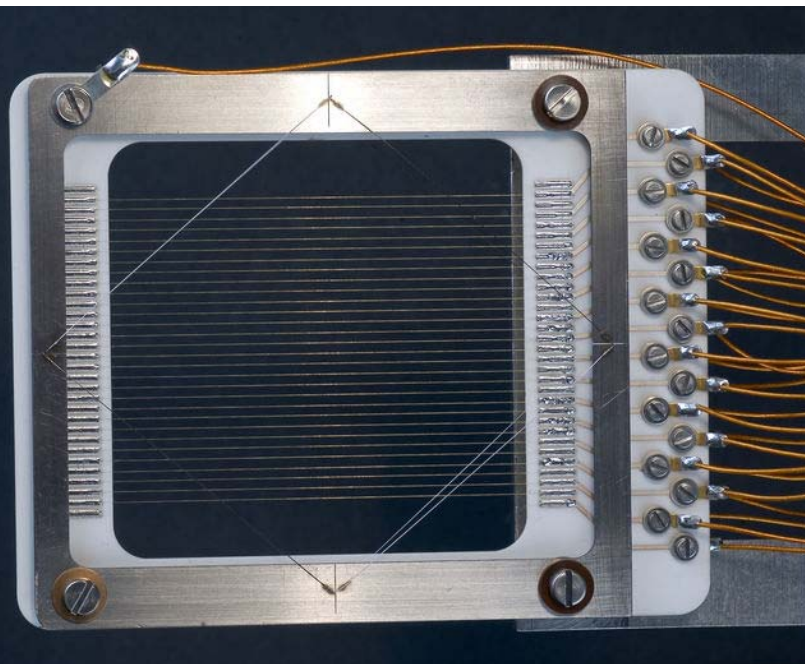
The current flowing back onto the ribbons is Measured

Electrons are taken away by polarisation voltage

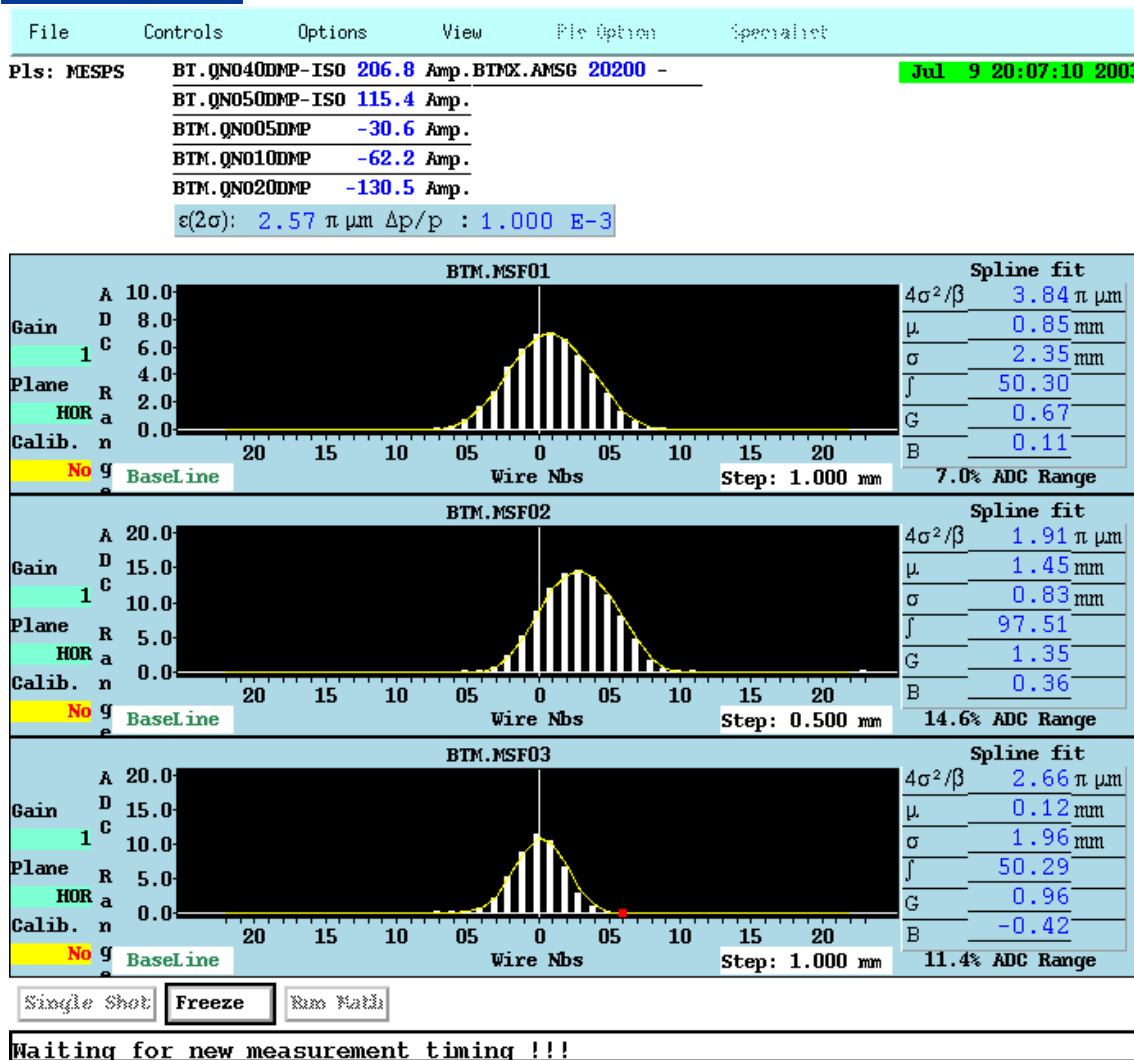
One amplifier/ADC chain channel per ribbon



SEM grids with wires



Profiles from SEMgrids



Projection of charge density projected to x or y axis is Measured

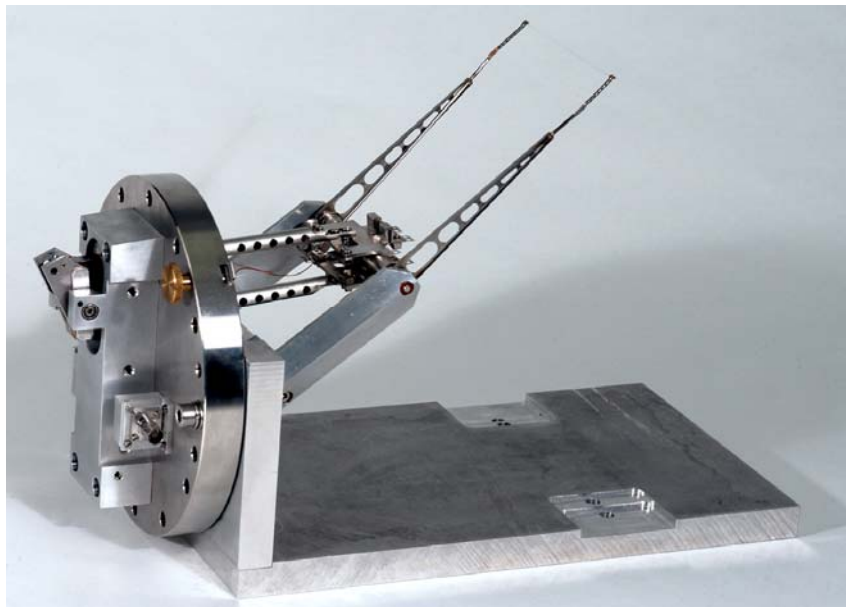
One amplifier/ADC per wire
Large dynamic range

Resolution is given by wire distance

Used only in transfer lines

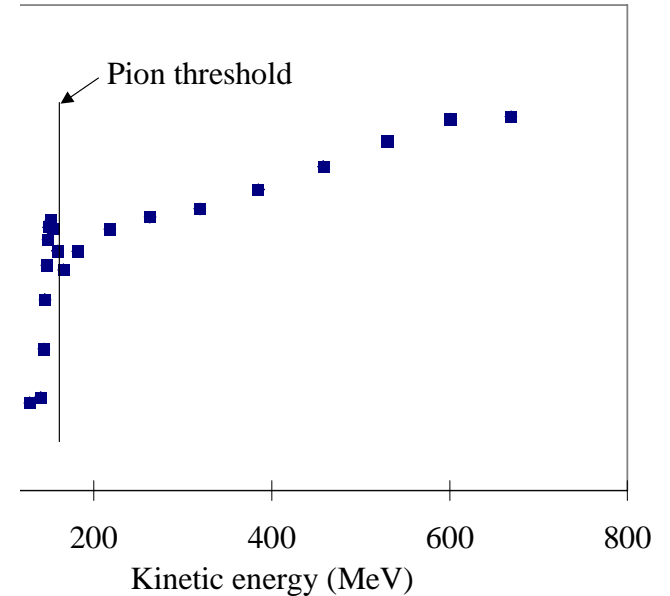
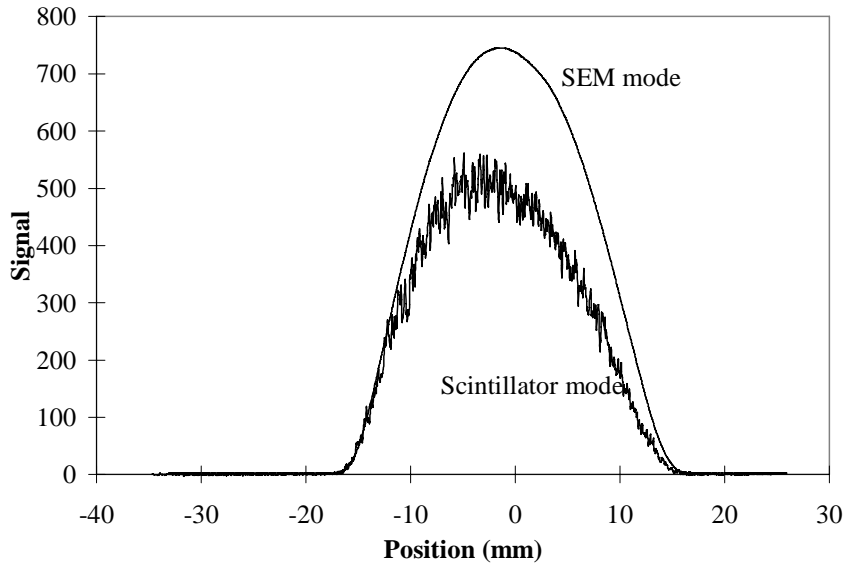
Wire Scanners

A thin wire is quickly moved across the beam
Secondary particle shower is detected outside the vacuum chamber
on a scintillator/photo-multiplier assembly
Position and photo-multiplier signal are recorded simultaneously

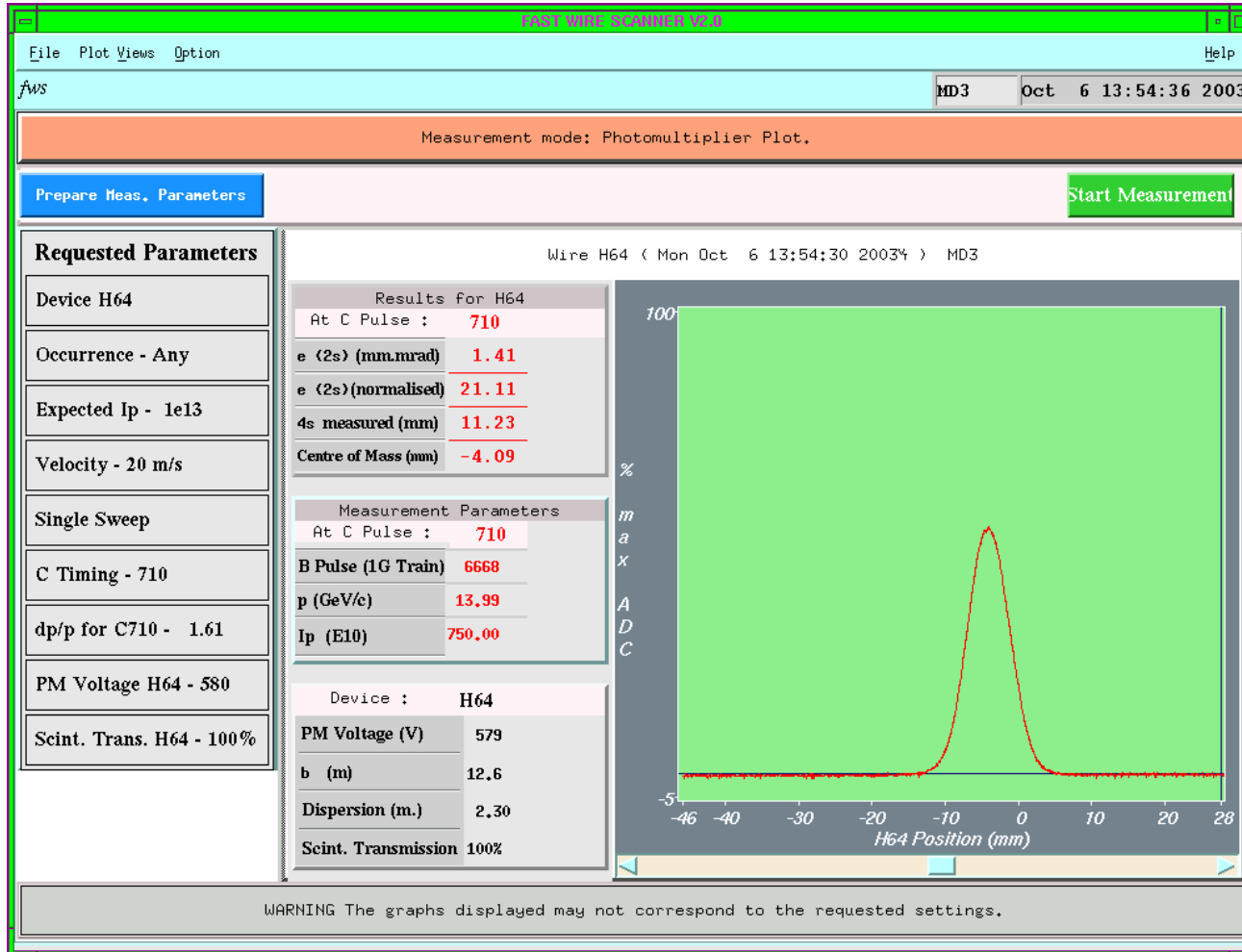


Problems at low energy

- Secondary particle shower intensity in dependence of primary



Wire scanner profile



High speed needed because of heating.

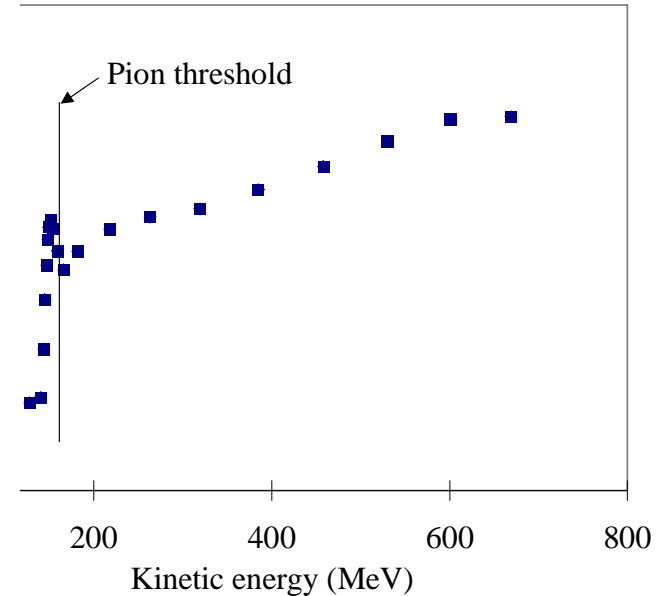
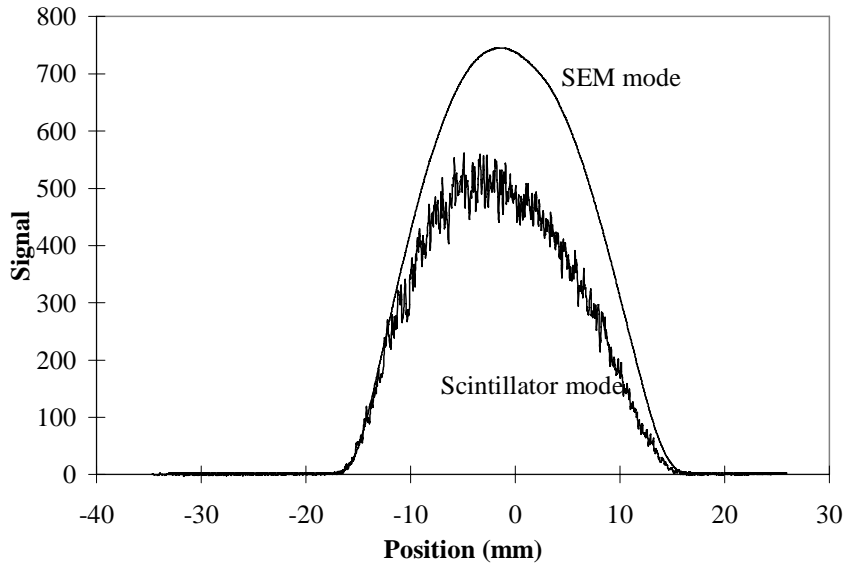
Adiabatic damping

Current increase due to Speed increase

Speeds of up to 20m/s => 200g acceleration

Problems at low energy

- Secondary particle shower intensity in dependence of primary

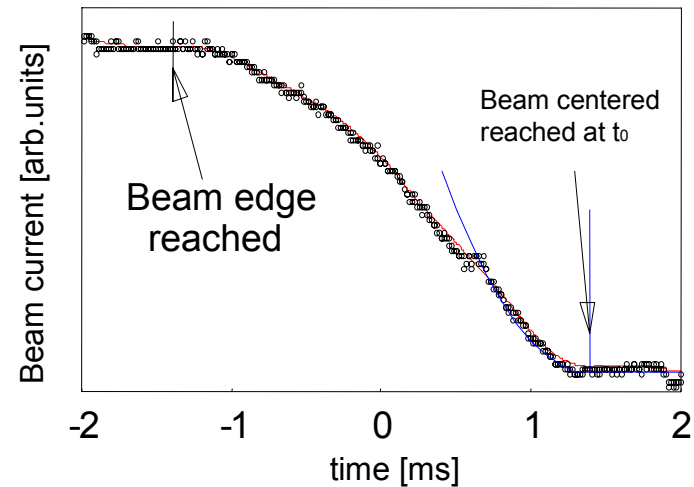


Wire scanners and partially stripped ions

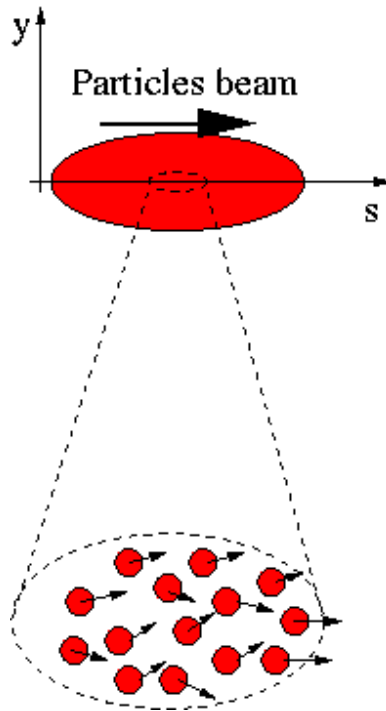
Partially stripped ions loose electrons when interacting with the wire

The beam is lost

Can measure amplitude distribution however



Emittance measurements

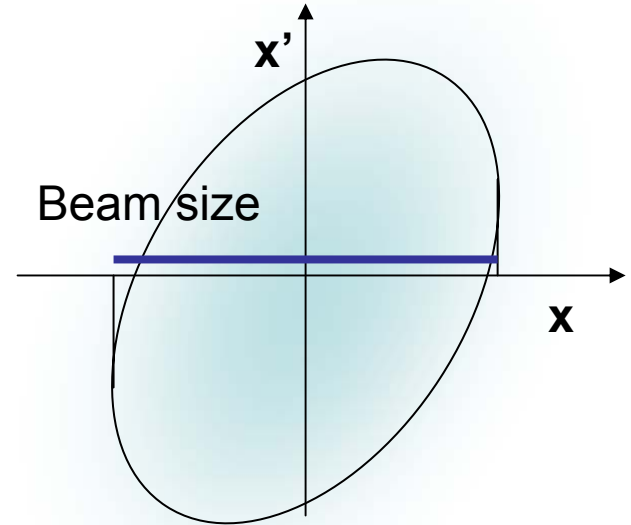


A beam is made of many many particles, each one of these particles is moving with a given velocity. Most of the velocity vector of a single particle is parallel to the direction of the beam as a whole (s). There is however a smaller component of the particles velocity which is perpendicular to it (x or y).

$$\vec{v}_{particle} = v_s \hat{u}_s + v_x \hat{u}_x + v_y \hat{u}_y$$

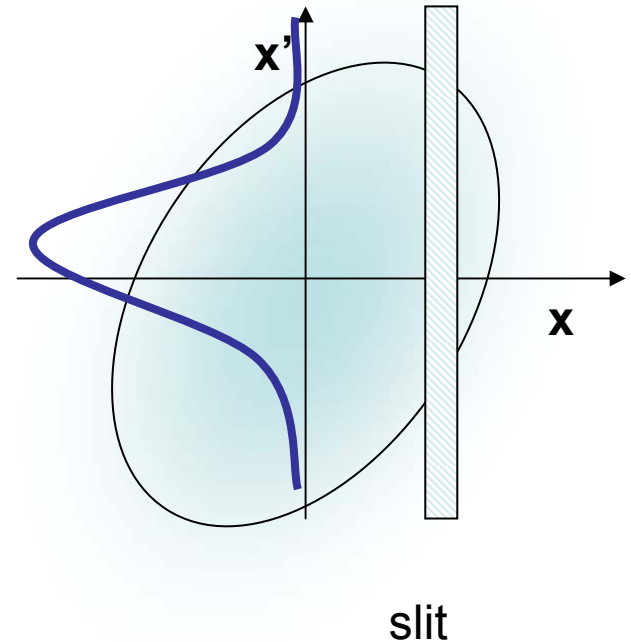
Emittance measurements

- If for each beam particle we plot its position and its transverse angle we get a particle distribution whose boundary is an usually ellipse.
- The projection onto the x axis is the beam size



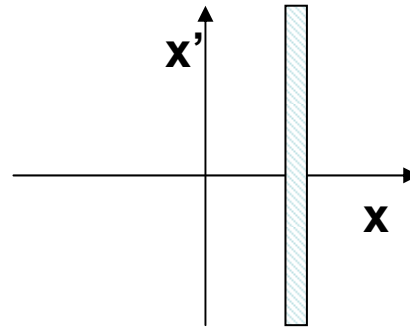
The slit method

- If we place a slit into the beam we cut out a small vertical slice of phase space
- Converting the angles into position through a drift space allows to reconstruct the angular distribution at the position defined by the slit



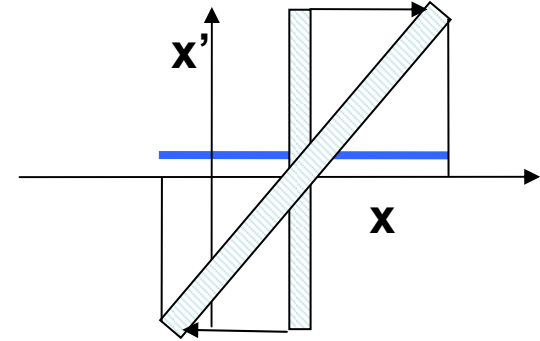
Transforming angular distribution to profile

- When moving through a **drift space** the angles don't change (**horizontal move** in phase space)
- When moving through a **quadrupole** the position does not change but the angle does (**vertical move** in phase space)



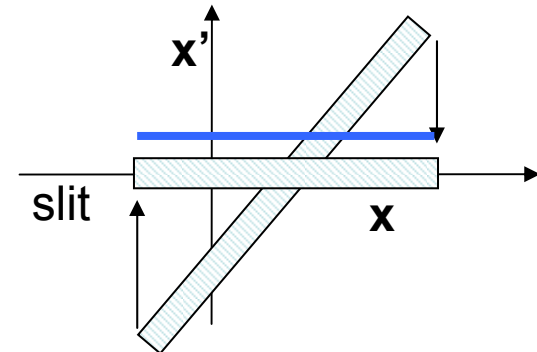
slit

Influence of a drift space



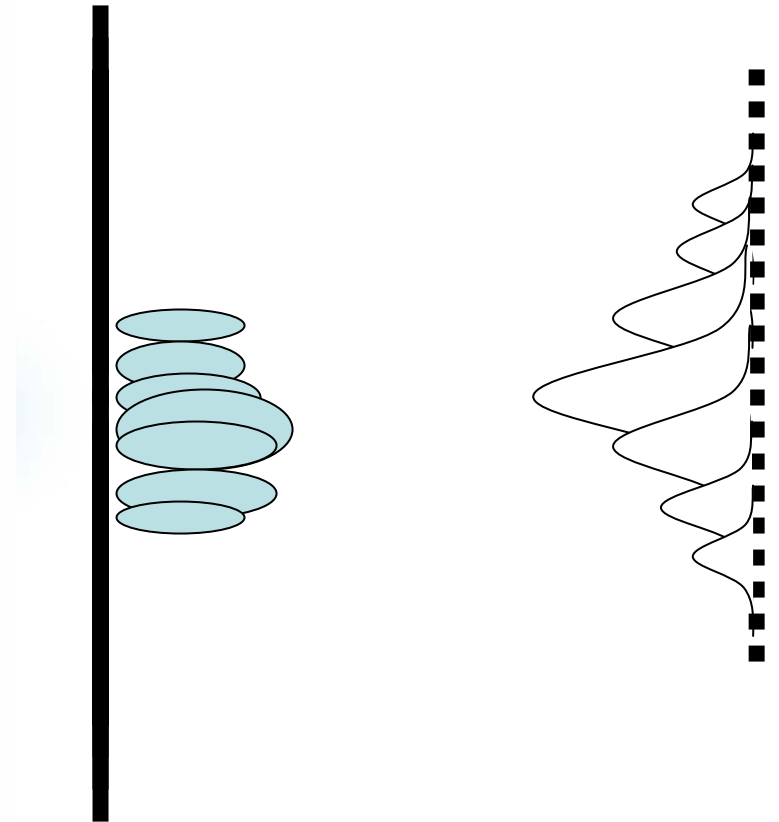
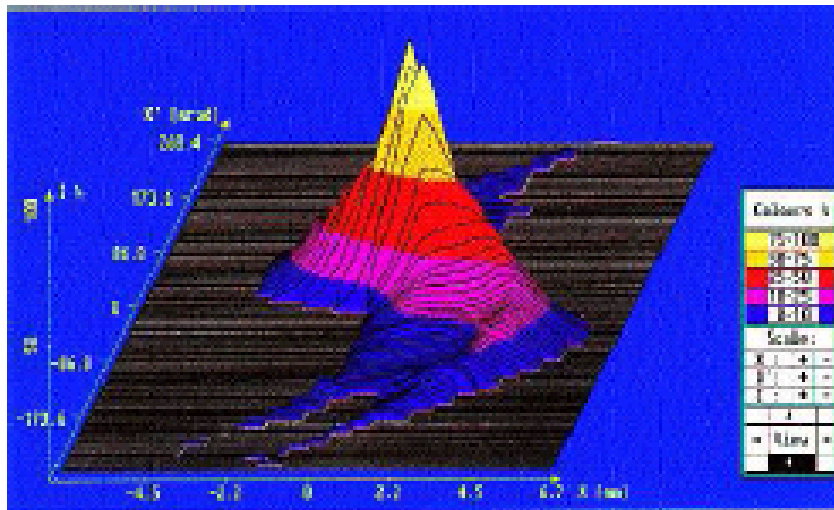
slit

Influence of a quadrupole



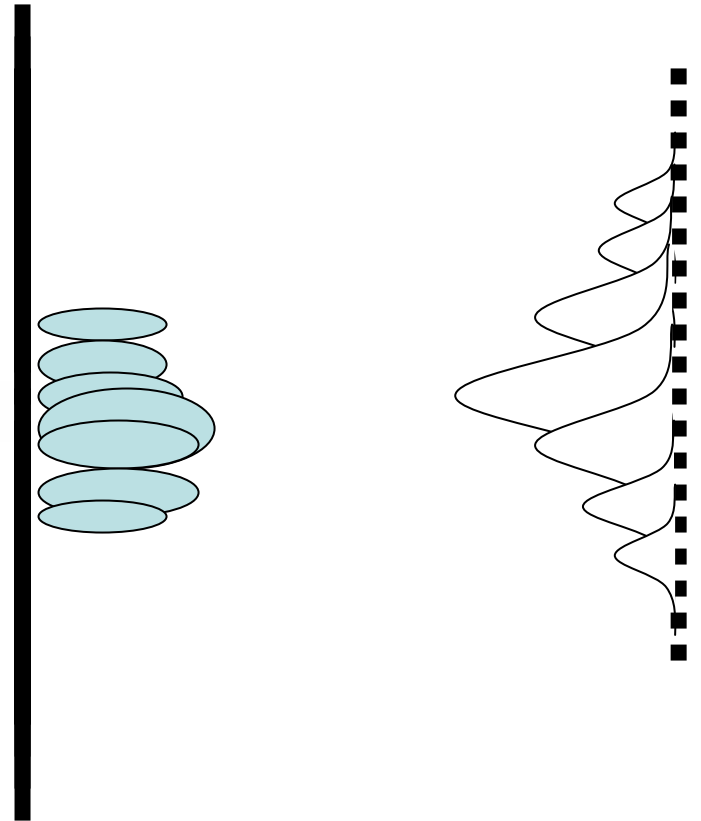
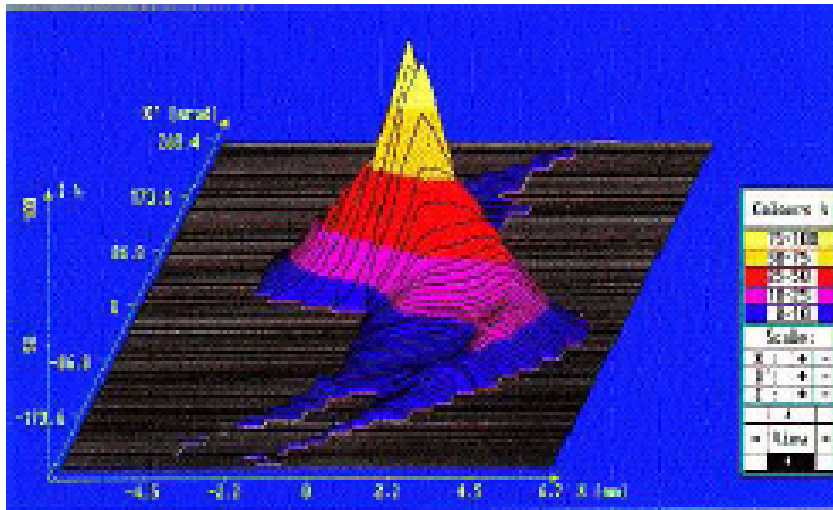
The Slit Method

3-dim plot:



The Slit Method

3-dim plot:

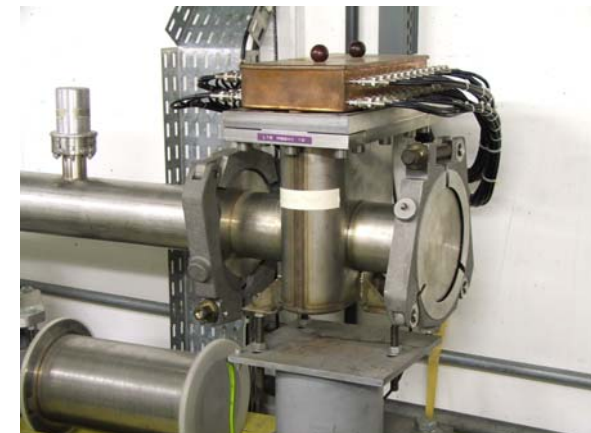
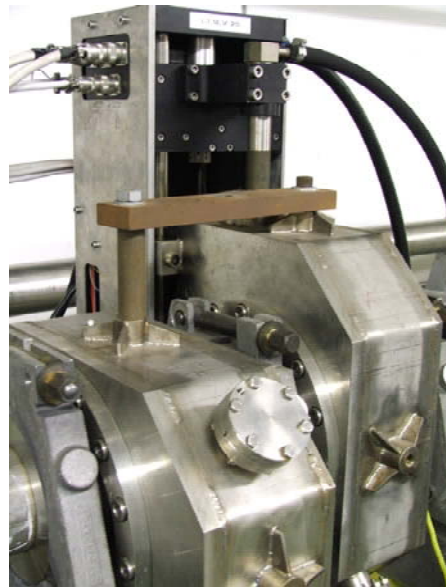
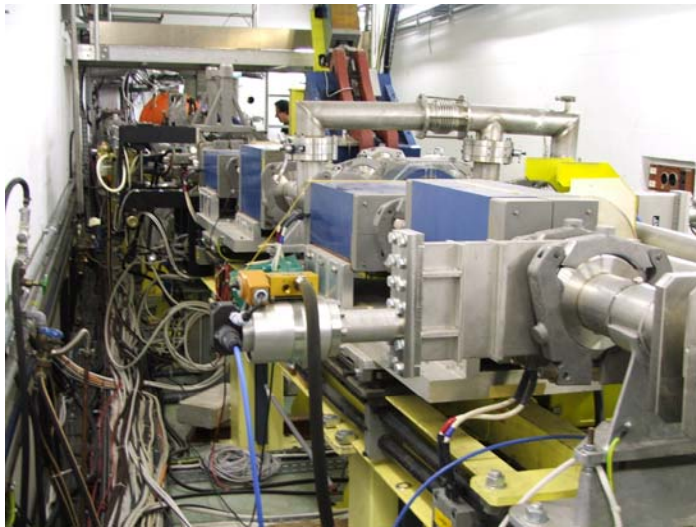
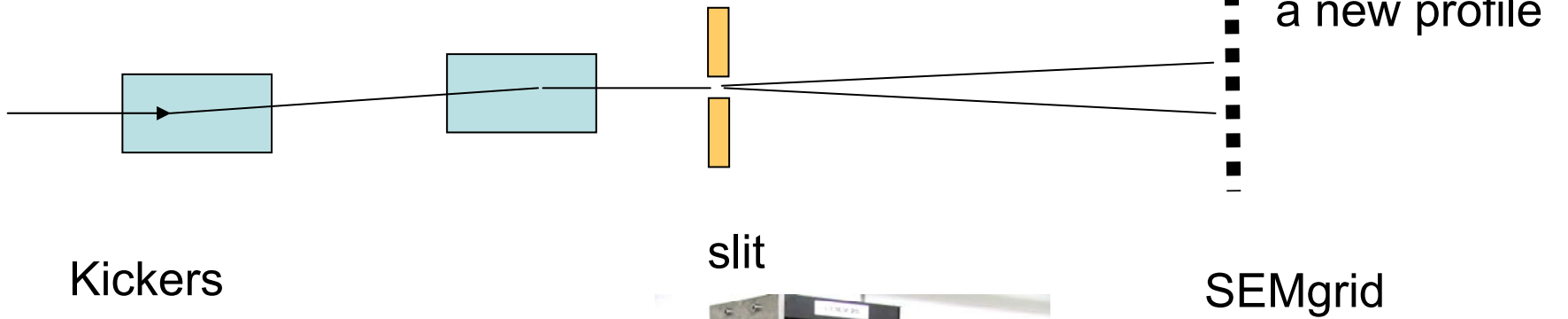




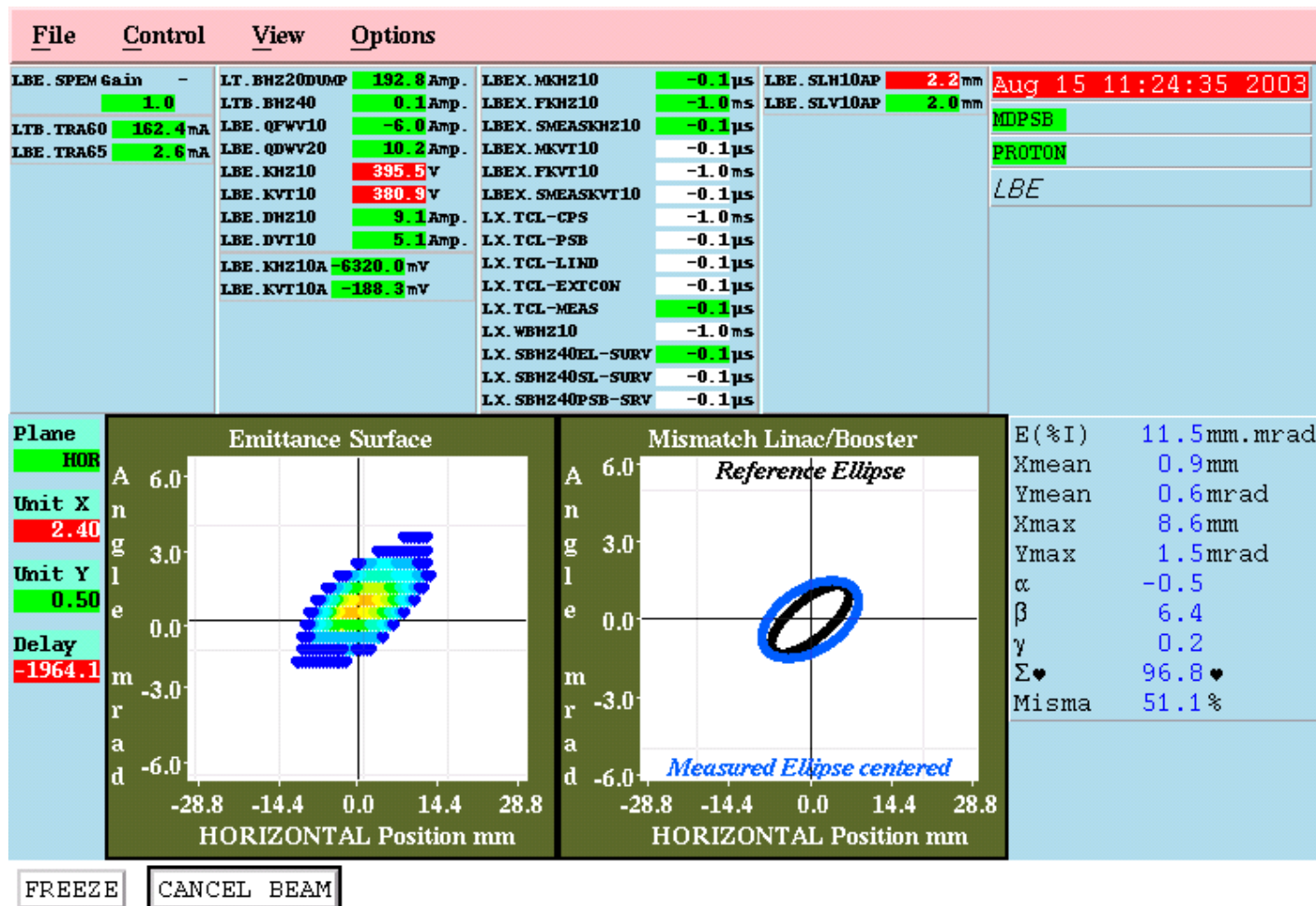
Moving slit emittance measurement

- Position resolution given by slit size and displacement
- Angle resolution depends on resolution of profile measurement device and drift distance
- High position resolution → many slit positions → slow
- Shot to shot differences result in measurement errors

Single pulse emittance measurement



Result of single pulse emittance measurement



Waiting for new acquisition...

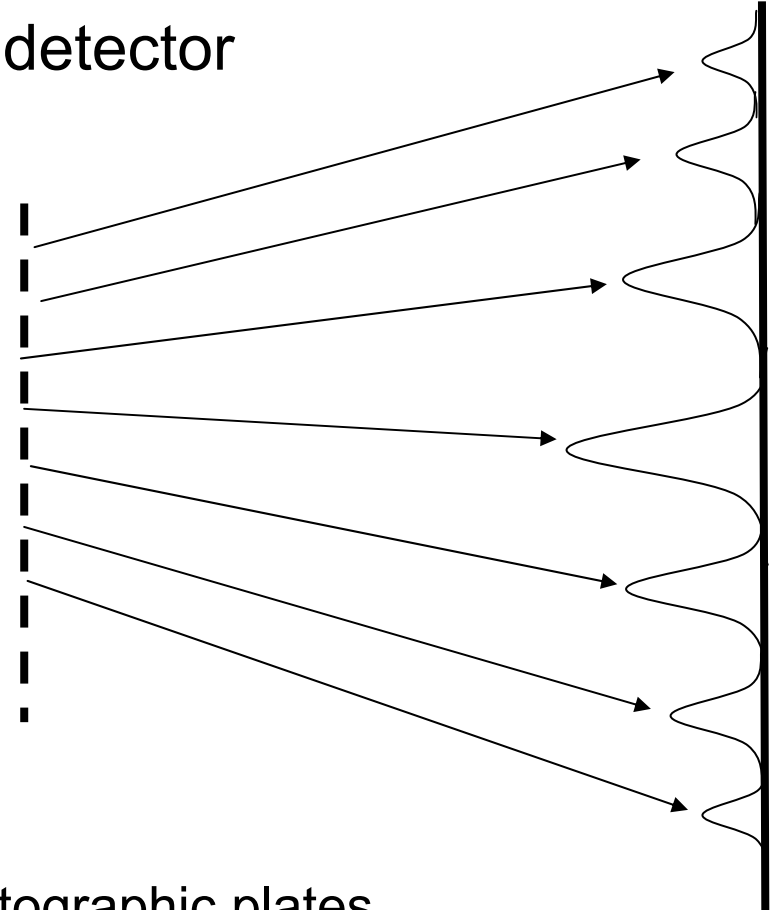
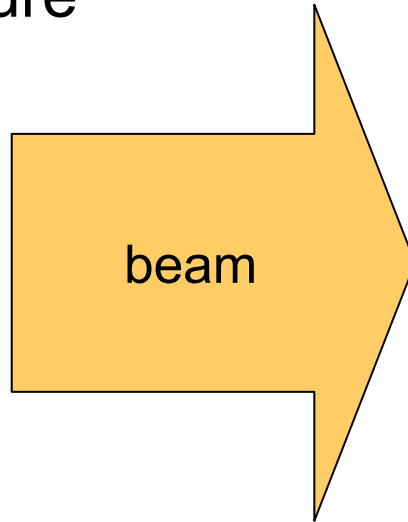


Single Shot Emittance Measurement

- Advantage:
 - Full scan takes 20 μ s
 - Shot by shot comparison possible
- Disadvantage:
 - Very costly
 - Needs dedicated measurement line
 - Needs a fast sampling ADC + memory for each wire
- Cheaper alternative:
 - Multi-slit measurement

Multi-slit measurement

- Needs high resolution profile detector
- Must make sure that profiles don't overlap



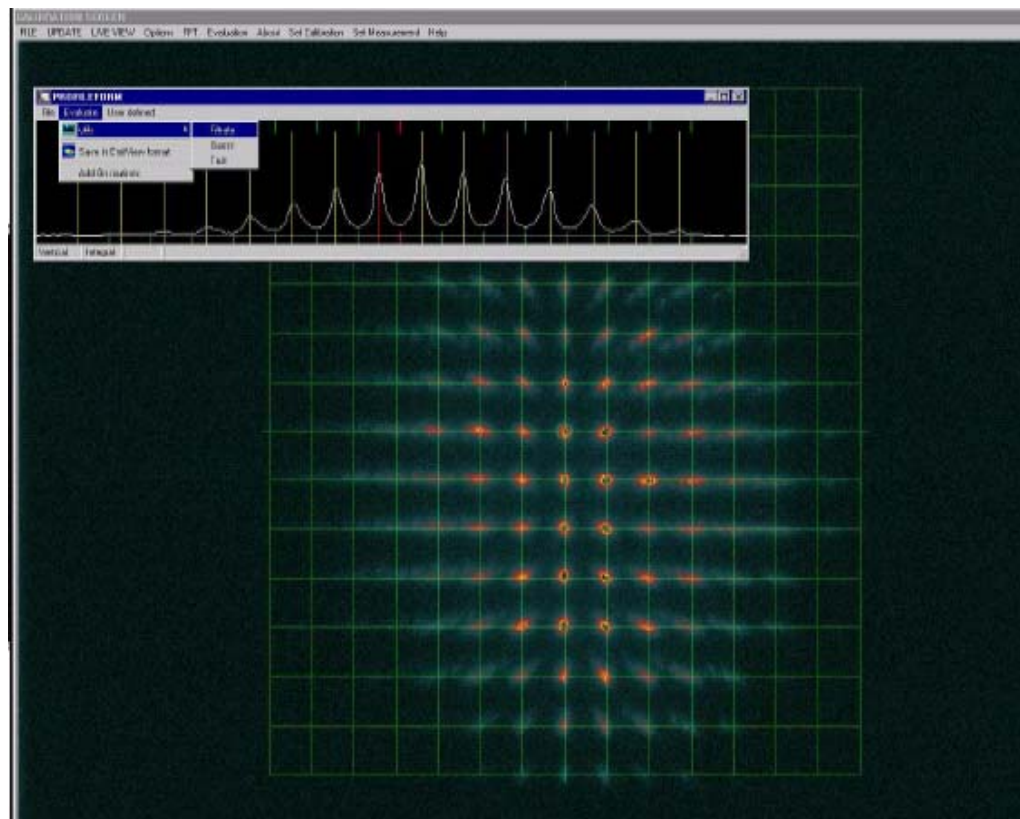
Scintillator + TV + frame grabber
often used as profile detector

Very old idea, was used with photographic plates

Pepperpot

Uses small holes instead of slits

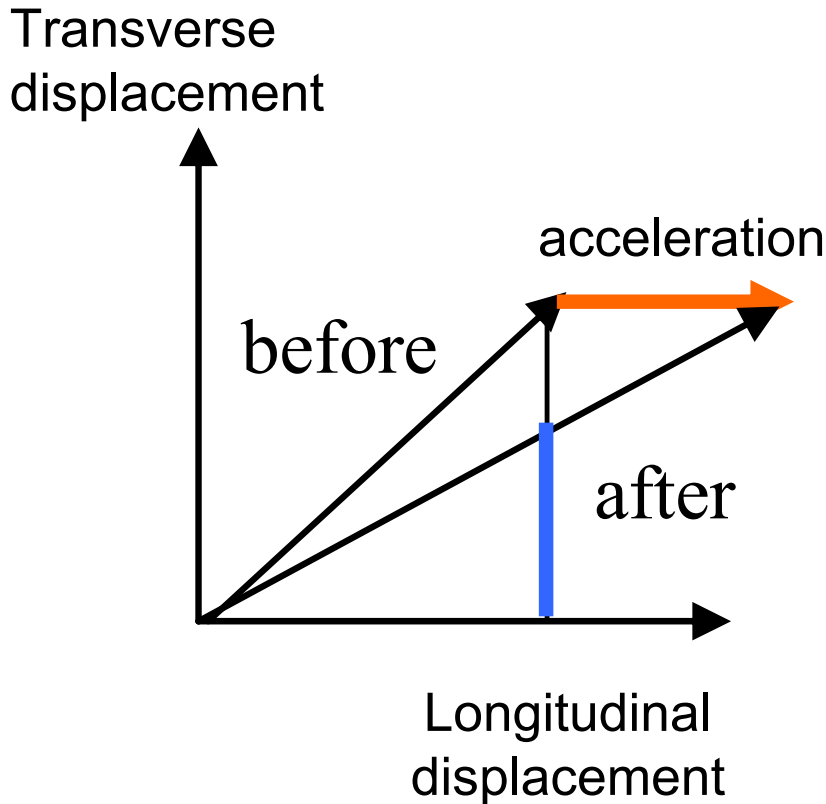
Measures horizontal and vertical emittance in a single shot



Adiabatic damping

- Change of emittance with acceleration

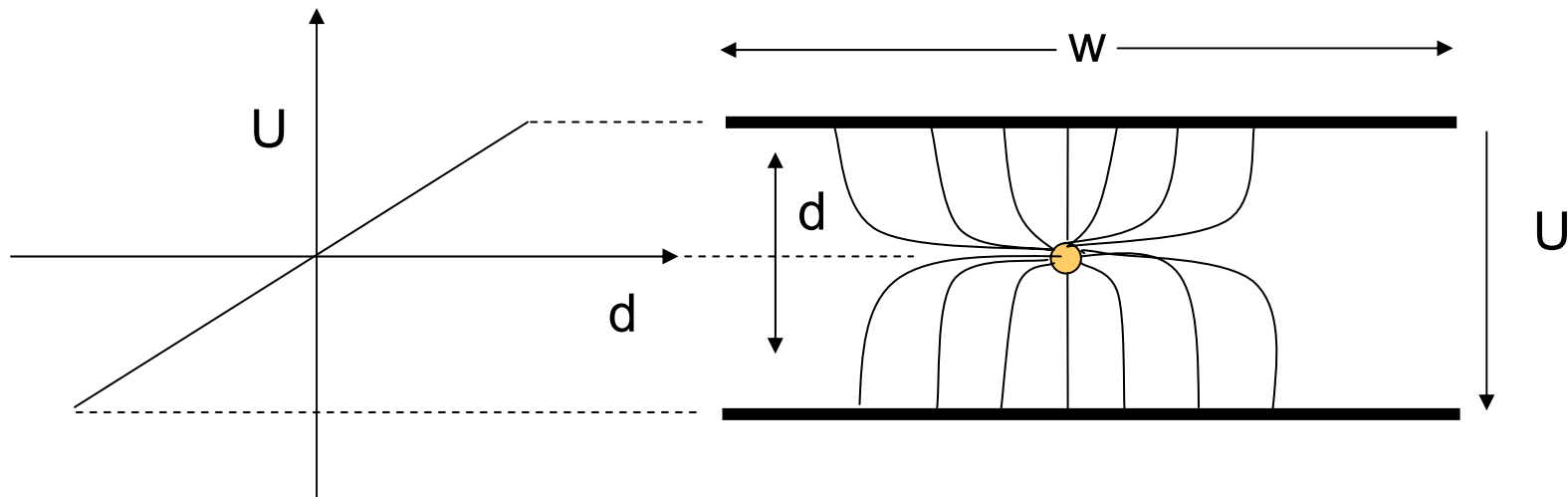
$$\varepsilon_{norm} = \varepsilon_{physical} \beta \gamma$$



β : speed
 γ : Lorentz factor

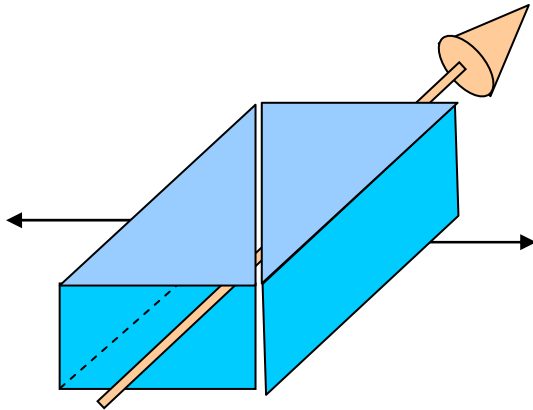
$$\gamma = \frac{1}{\sqrt{1 - \beta^2}}$$

Position measurements

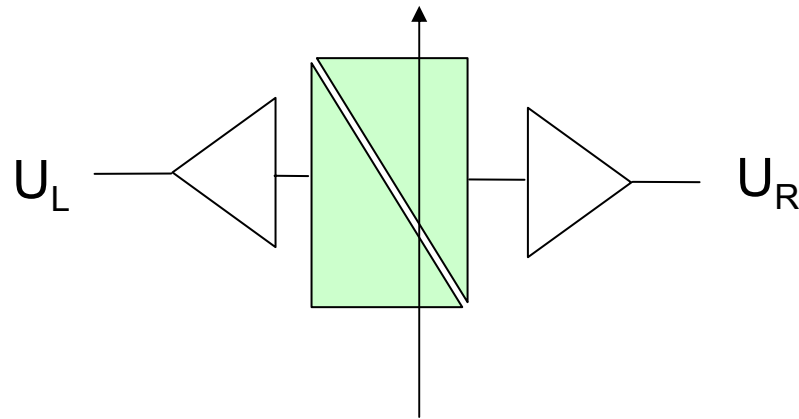


If the beam is much smaller than w , all field lines are captured and U is a linear function with displacement
 else: Linear cut (projection to measurement plane must be linear)

Shoebox pick-up



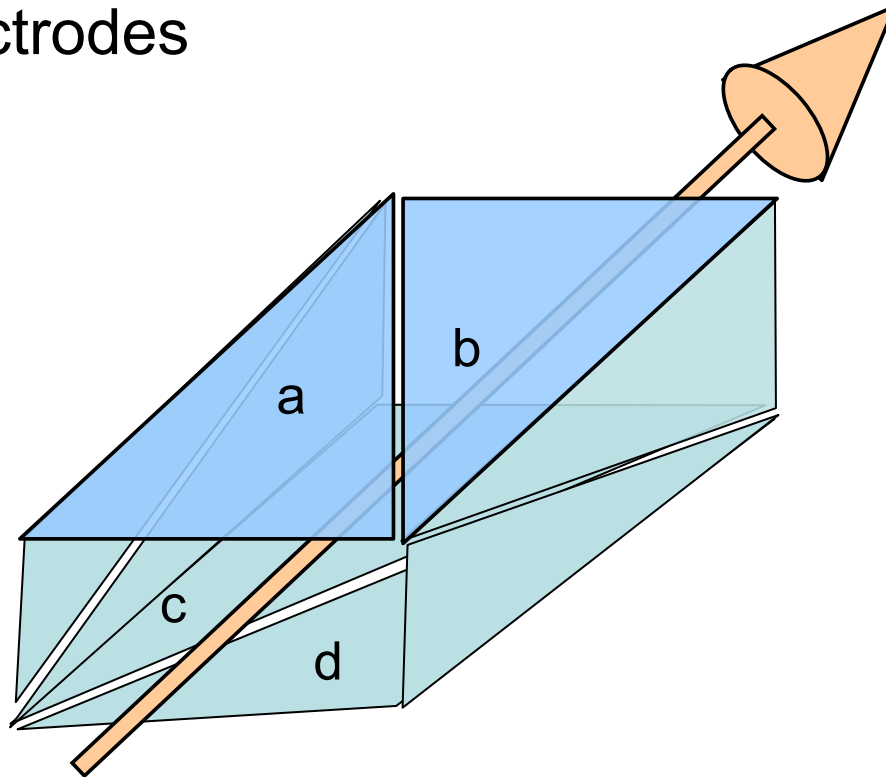
Linear cut through a shoebox



$$X \propto \frac{U_L - U_R}{U_L + U_R} = \frac{\Delta}{\Sigma}$$

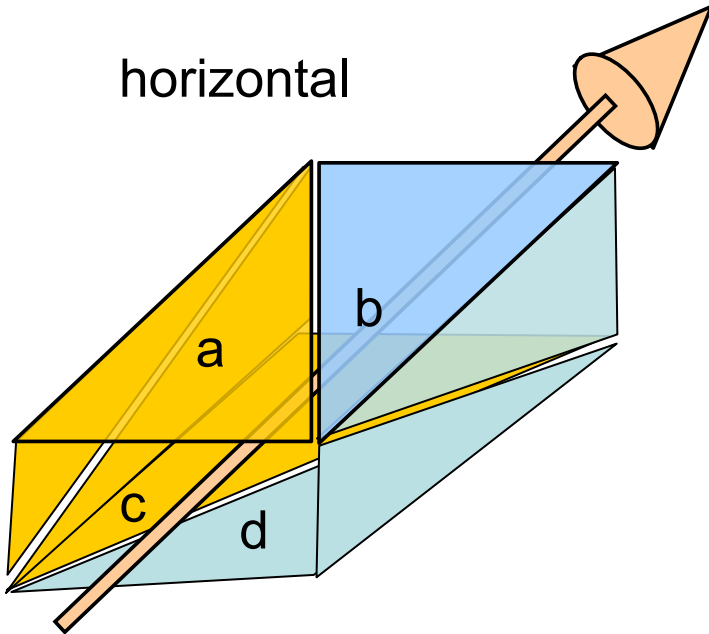
Doubly cut shoebox

- Can measure horizontal and vertical position at once
- Has 4 electrodes



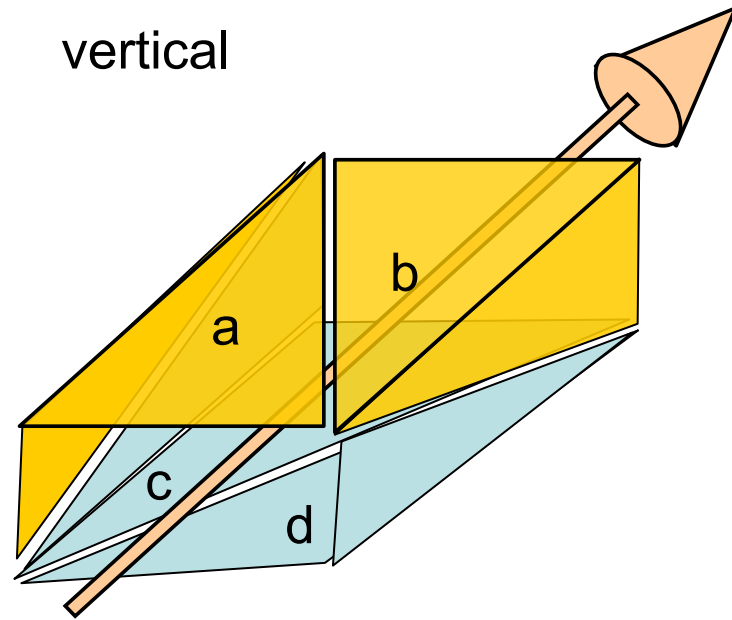
Simultaneous horizontal and vertical measurement

horizontal



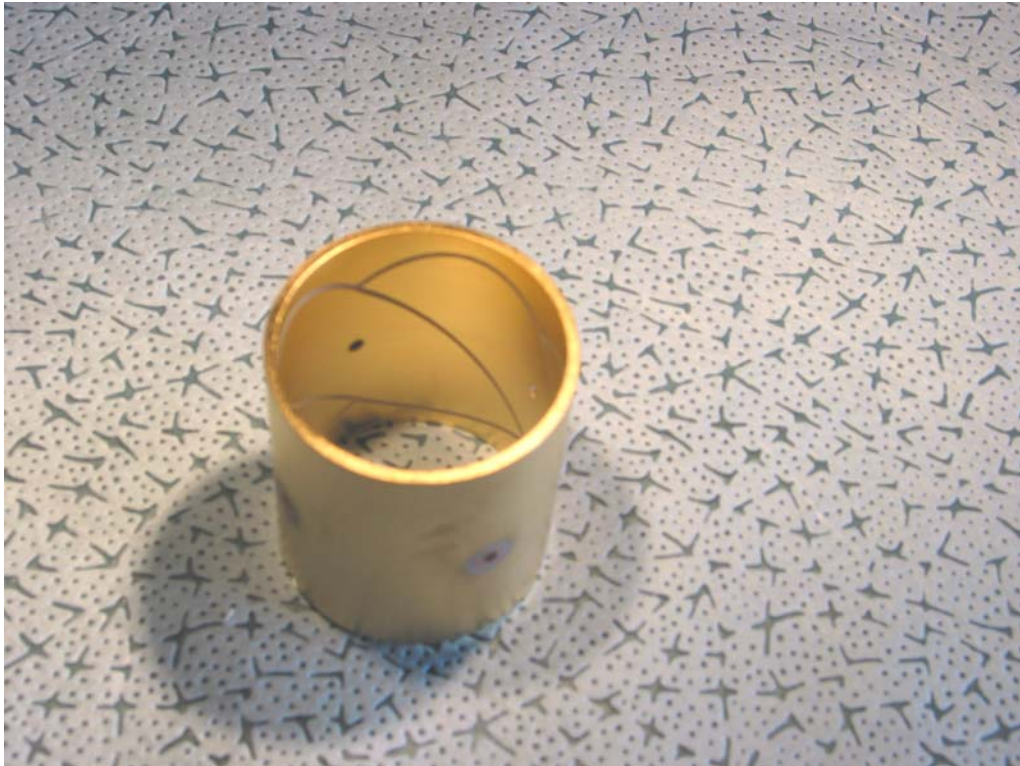
$$X = \frac{(U_a + U_c) - (U_b + U_d)}{\Sigma U}$$

vertical



$$Y = \frac{(U_a + U_b) - (U_c + U_d)}{\Sigma U}$$

Photo of a cylindrical pick-up



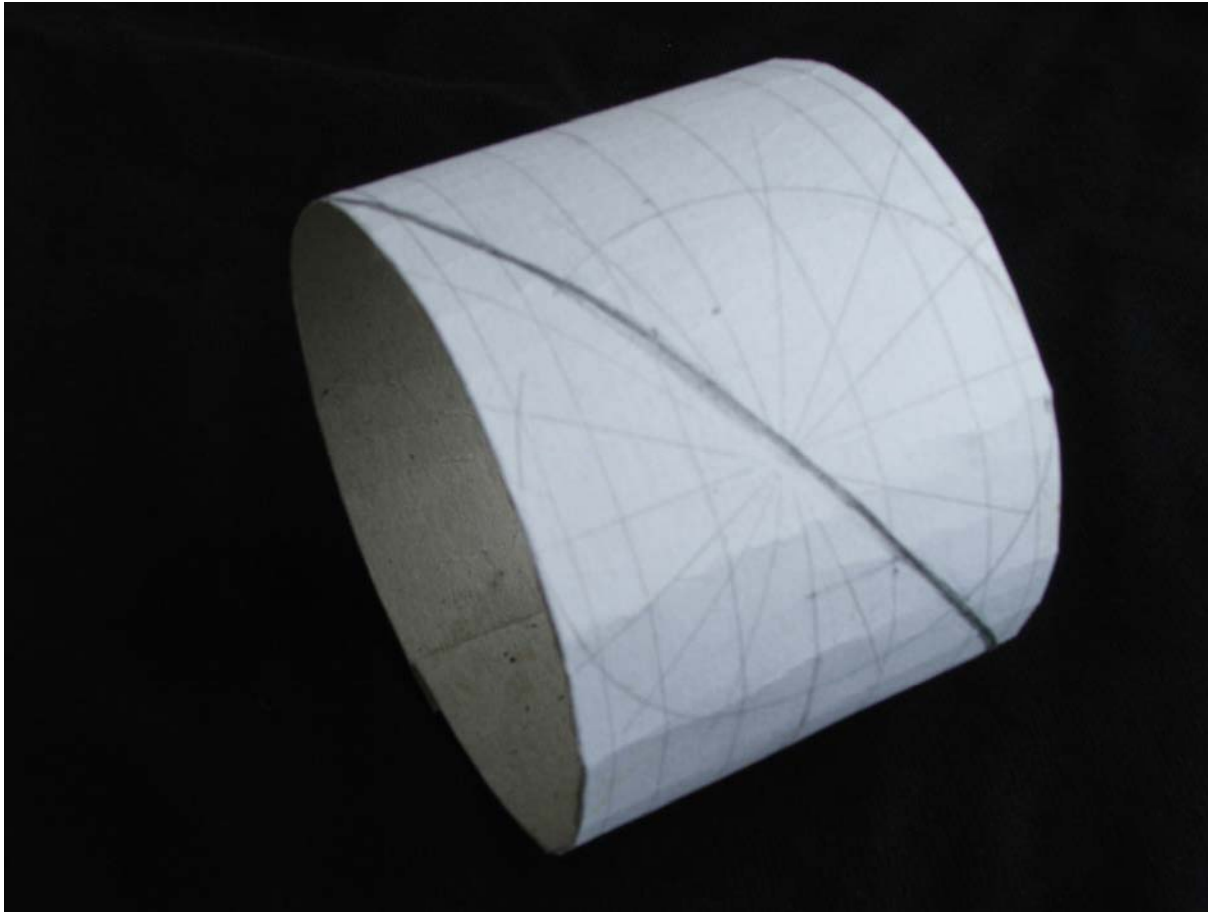
The cuts can be made by photo chemical means or mechanically

Here done with a sand-blasting device

A cylindrical pick-up with its connections

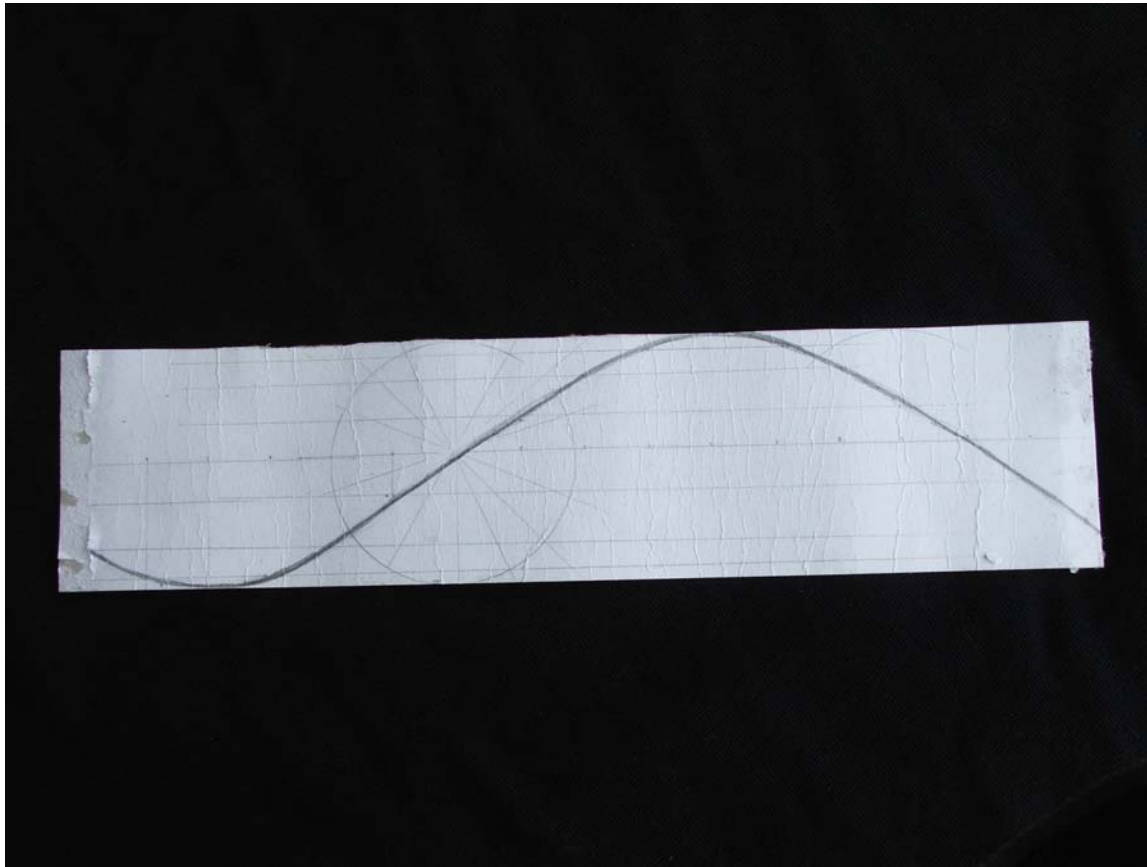
Building a cylindrical paper pick-up

- A linear cut in a cylinder:



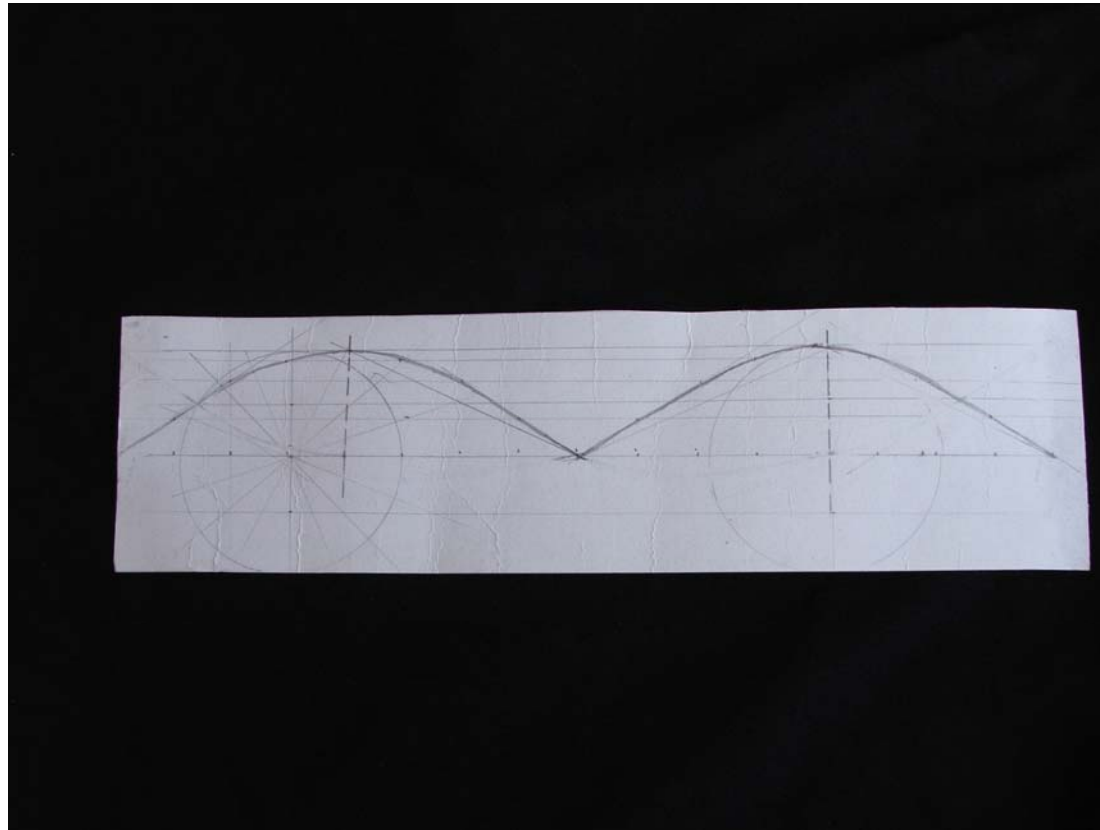
Unfolding the cylinder

- When unfolded the cut becomes a sine curve



Flipping the sine curve

What happens if we flip use $\text{abs}(\sin(x))$ instead?
Mirror the negative sine part?

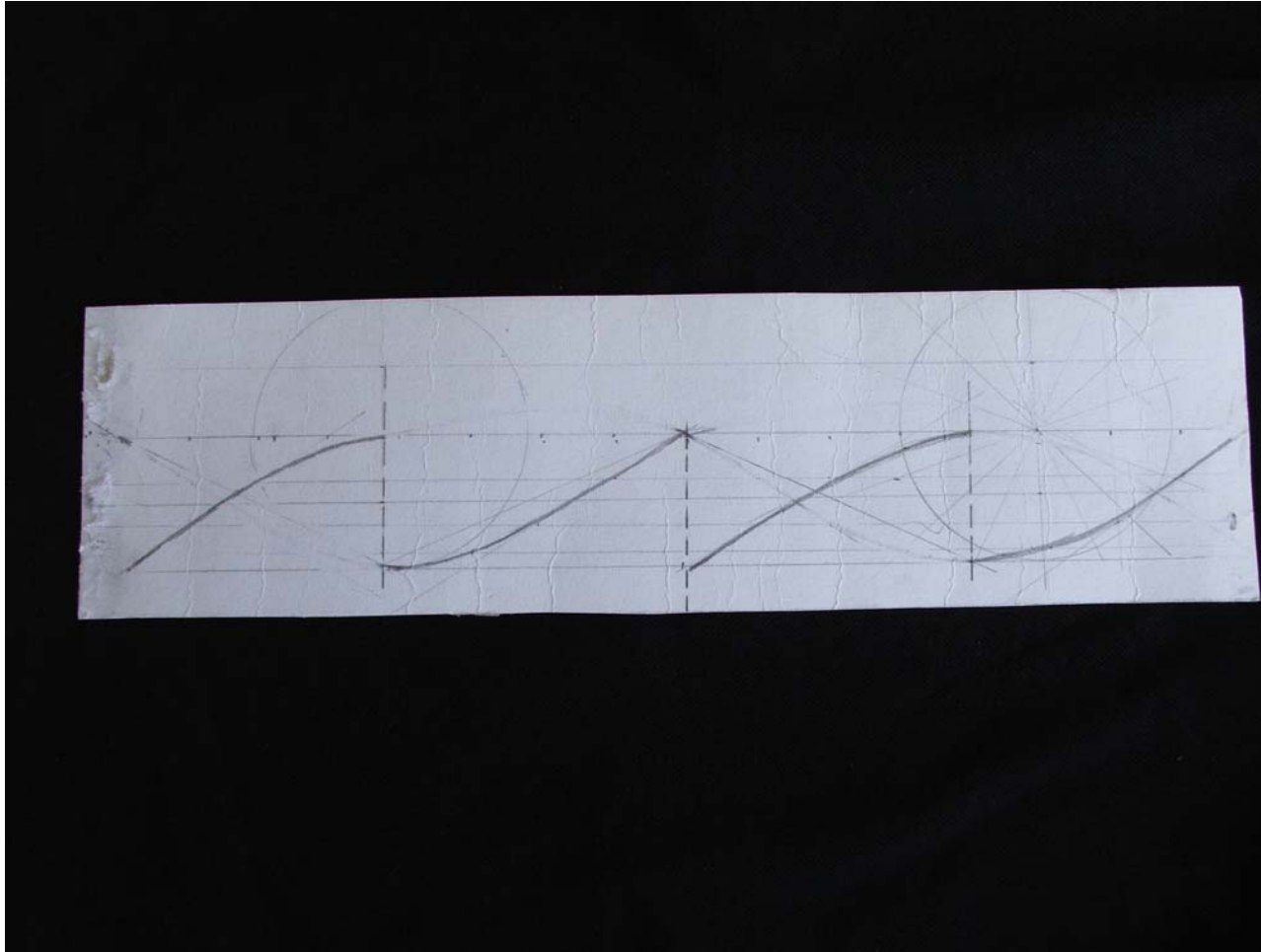


The cylinder is cut twice!

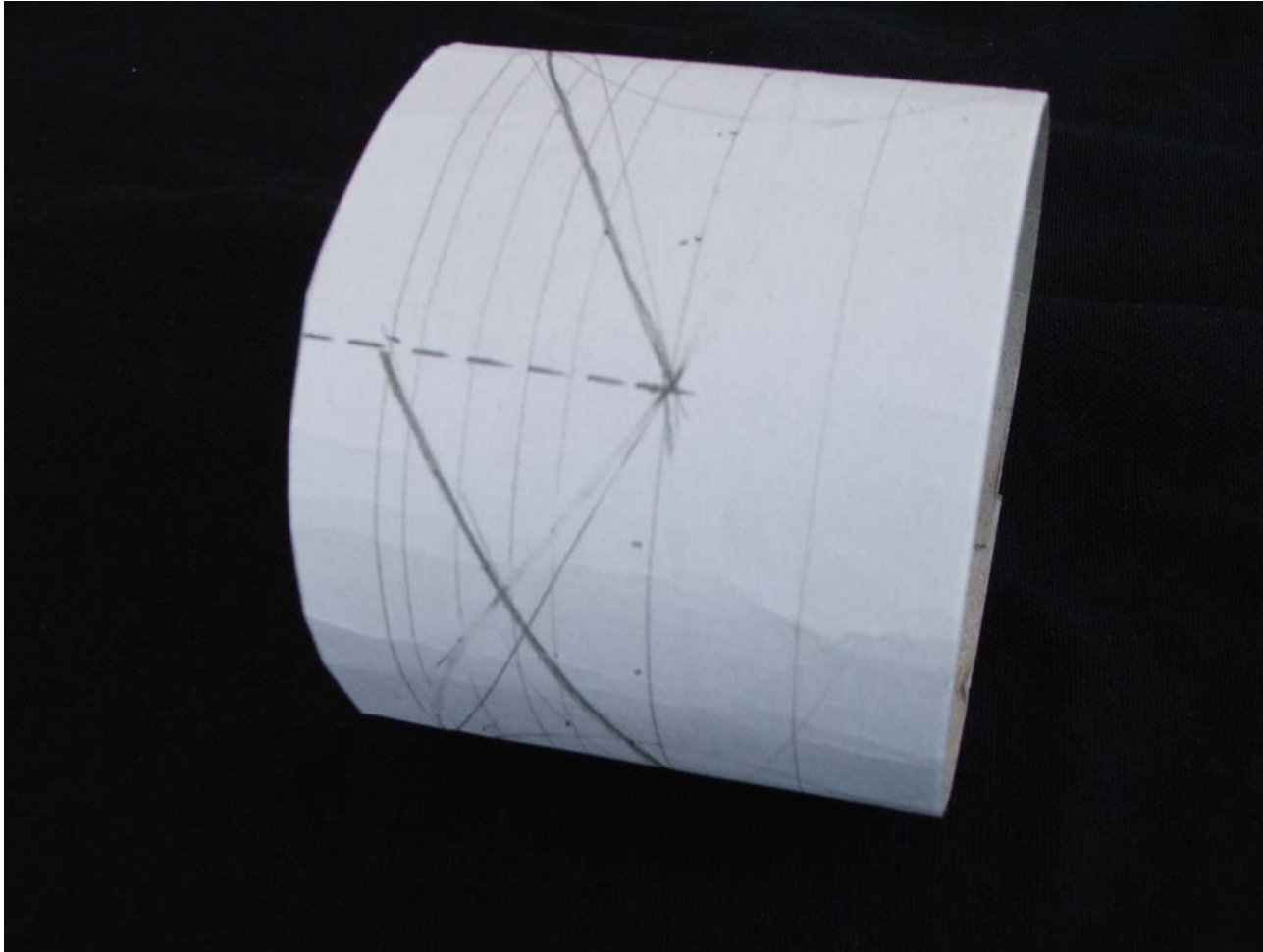


- Horizontal and vertical cut

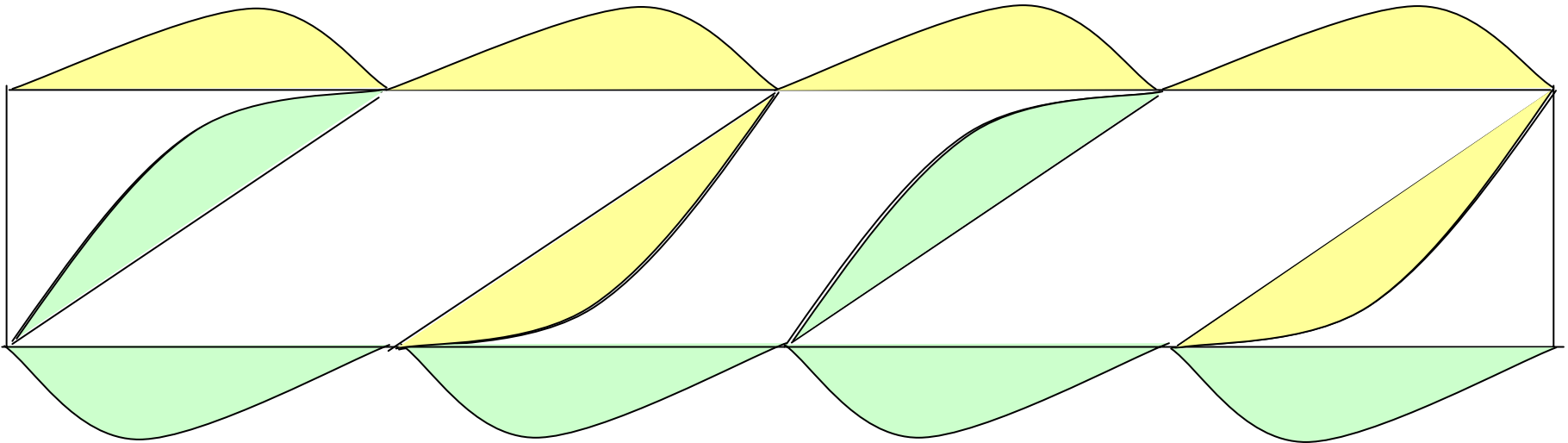
Flipping half the sin curve upside down



Cut in the same direction



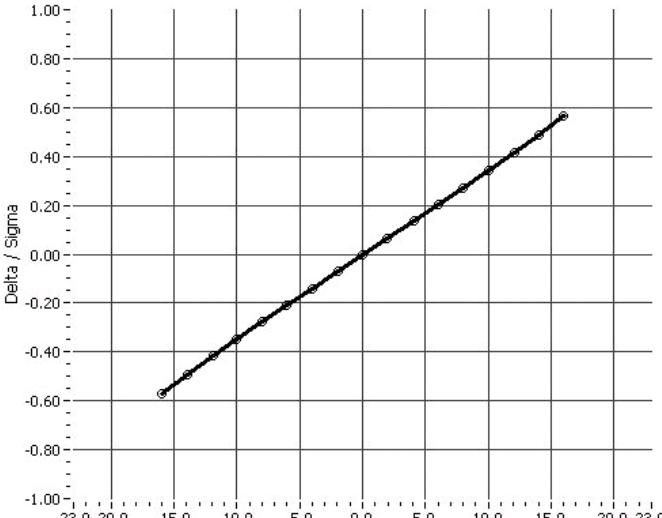
Using all the electrode surface



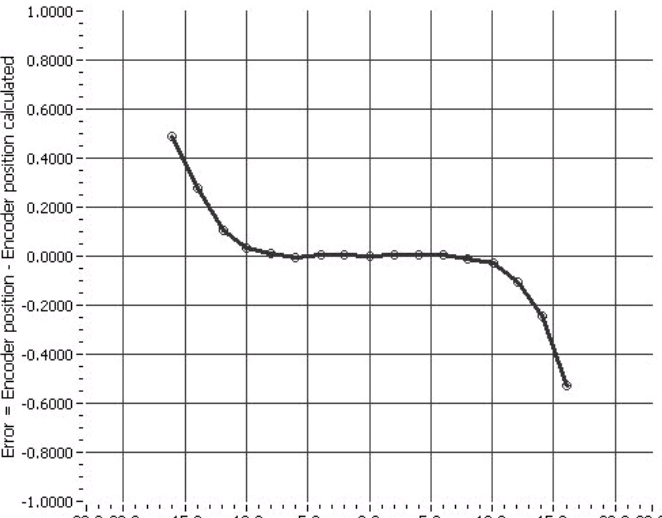
Calibration of the pick-up

PICK-UP SEMI AUTOMATED CALIBRATION BENCH -- GRAPHS RESULTS

Author's name <input type="text"/>	Pick-Up name <input type="text" value="BPE"/>	Front end name <input type="text" value="Buffer hybrid"/>	Comments <input type="text"/>
Date <input type="text" value="26 09 2003"/>	Pick-Up number <input type="text" value="2"/>	Pick-Up diameter (mm) <input type="text" value="46"/>	Front end number <input type="text" value="1"/>



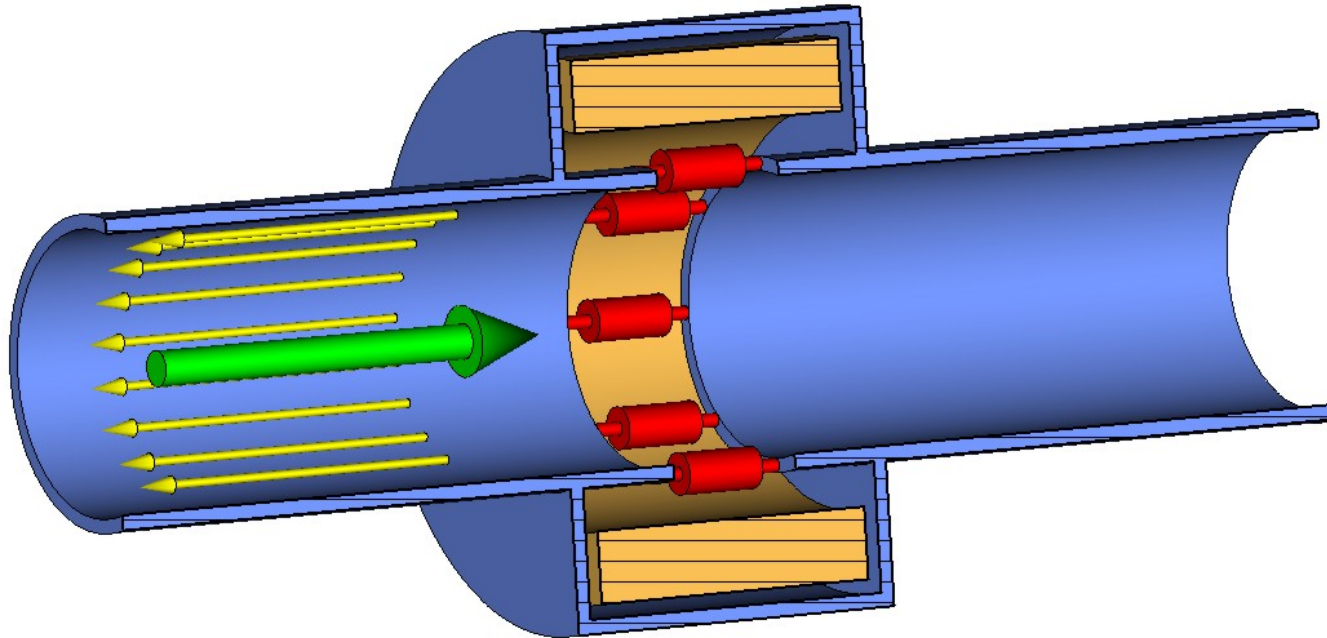
GENERAL GRAPH



ERROR GRAPH

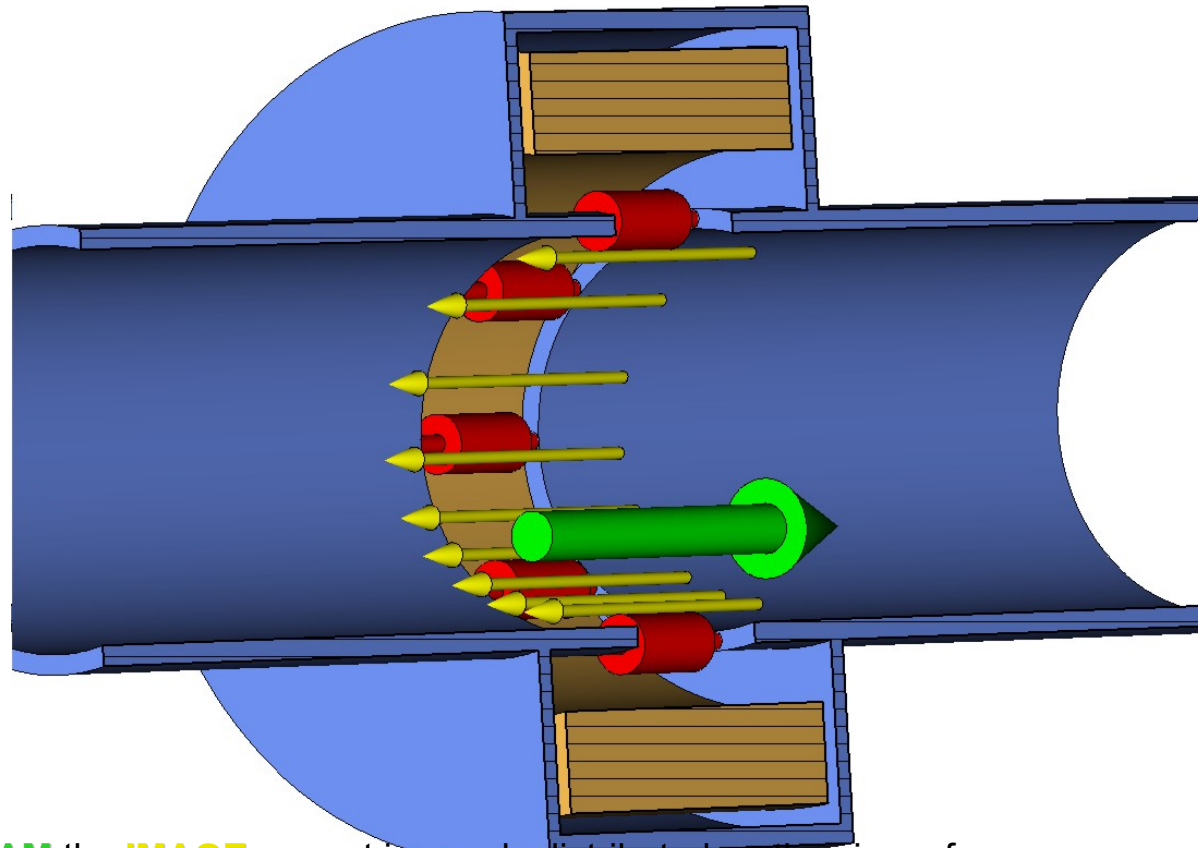
General	Curve fitting	Polynomial Coefficients
Step size: <input type="text" value="2"/> Number of points: <input type="text" value="17"/> Offset (mm): <input type="text" value="0.00"/> Mechanical zero (mm): <input type="text" value="0.00"/> Scanned: <input checked="" type="button" value="Vertically"/>	Max Error D/5: <input type="text" value="0.5289"/> Max Error S (V): <input type="text" value="0.0003"/> FE installed? (coef.): <input checked="" type="checkbox"/> <input type="text" value="0.0000"/> Impedance (Ohms): <input type="text" value="0.000E+0"/>	Equation of fitted curve Delta / Sigma $\text{Delta / Sigma} = +102.661E-3 + 29.200E+0 \text{ Pos}$

Wall Current Monitor (WCM) principle



- The **BEAM** current is accompanied by its **IMAGE**
- A voltage proportional to the beam current develops on the **RESISTORS** in the beam pipe gap
- The gap must be closed by a box to avoid floating sections of the beam pipe
- The box is filled with the **FERRITE** to force the image current to go over the resistors
- The ferrite works up to a given frequency and lower frequency components flow over the box wall

WCM as a Beam Position Monitor



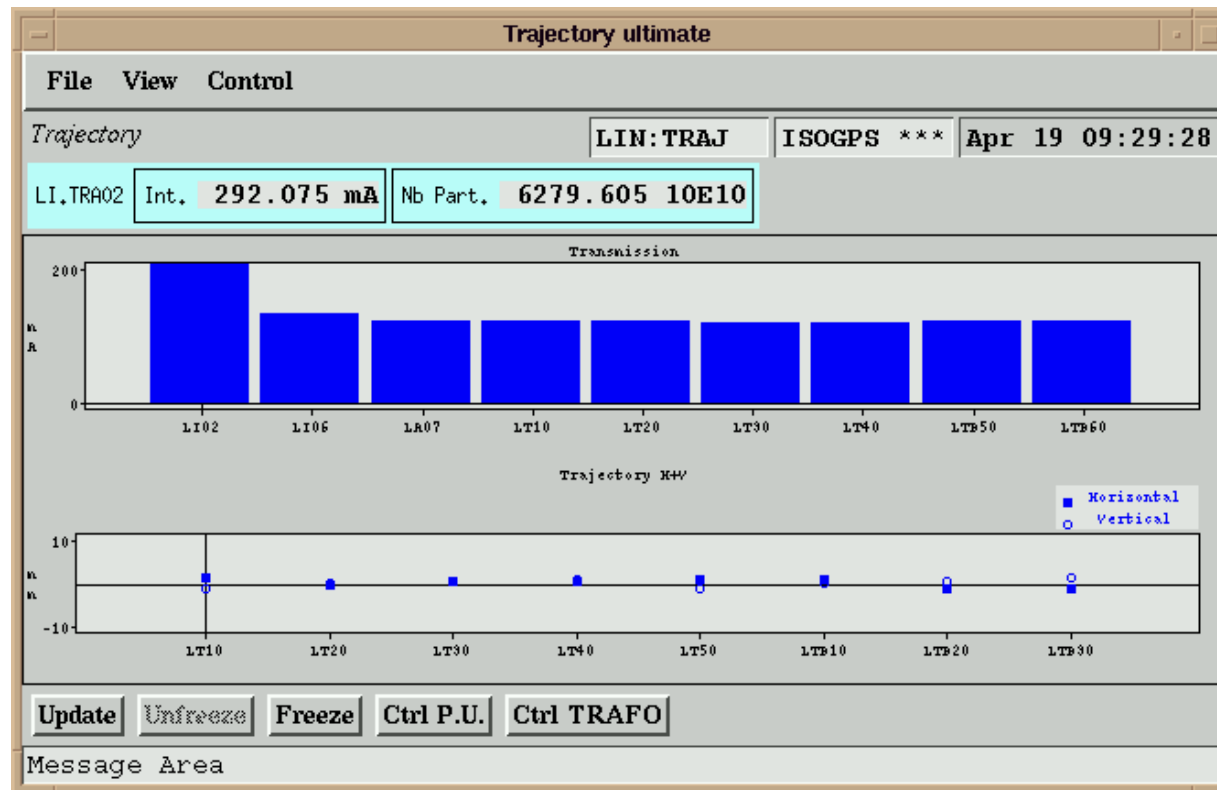
$$f_{L\Sigma} = \frac{R}{2\pi L_\Sigma}$$

$$f_{L\Delta} = \frac{R}{2\pi L_\Delta}$$

- For a centered **BEAM** the **IMAGE** current is evenly distributed on the circumference
- The image current distribution on the circumference changes with the beam position
- Intensity signal (Σ) = resistor voltages summed
- Position dependent signal (Δ) = voltages from opposite resistors subtracted
- The Δ signal is also proportional to the intensity, so the position is calculated according to Δ/Σ
- Low cut-offs depend on the gap resistance and box wall (for Σ) and the pipe wall (for Δ) inductances

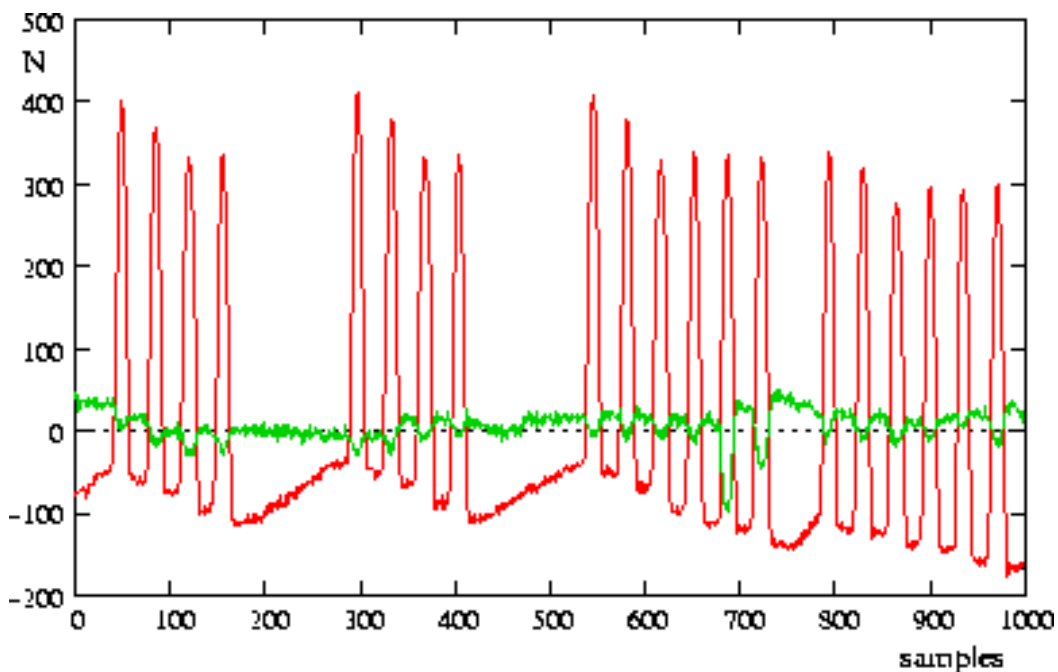
Measurement with pick-ups

- Trajectory measurements in transfer lines
- Control beam steering



Trajectory measurements in circular machines

- Needs integration gate
- Can be rather tricky
- Distance between bunches changes with acceleration
- Number of bunches may change

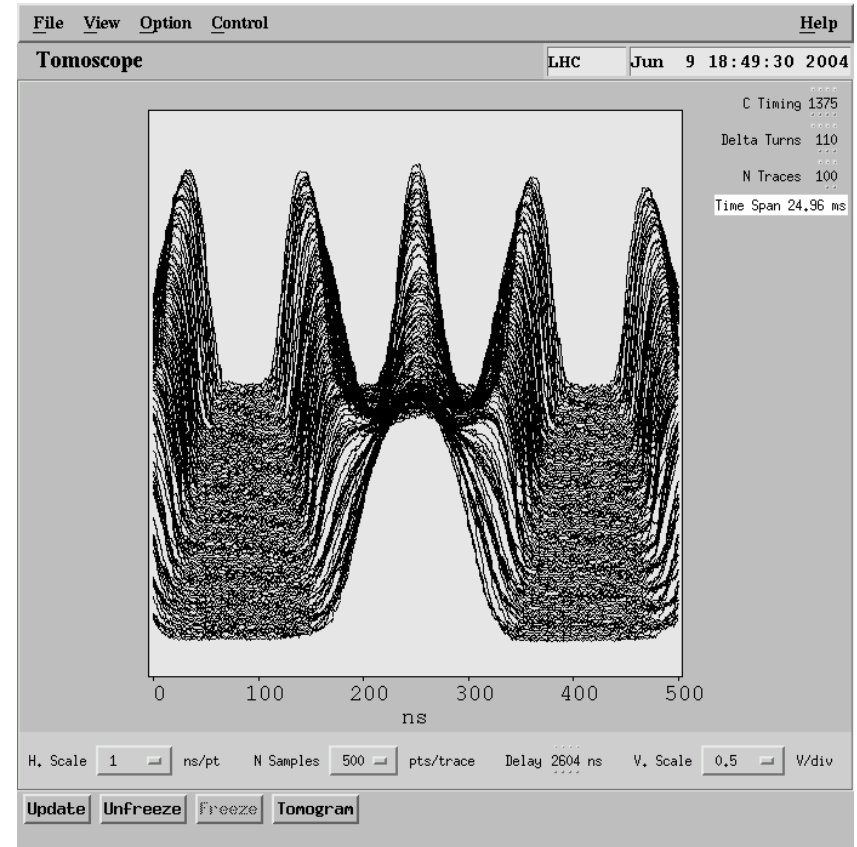


Raw data from pick-ups
double batch injection

Changing bunch frequency

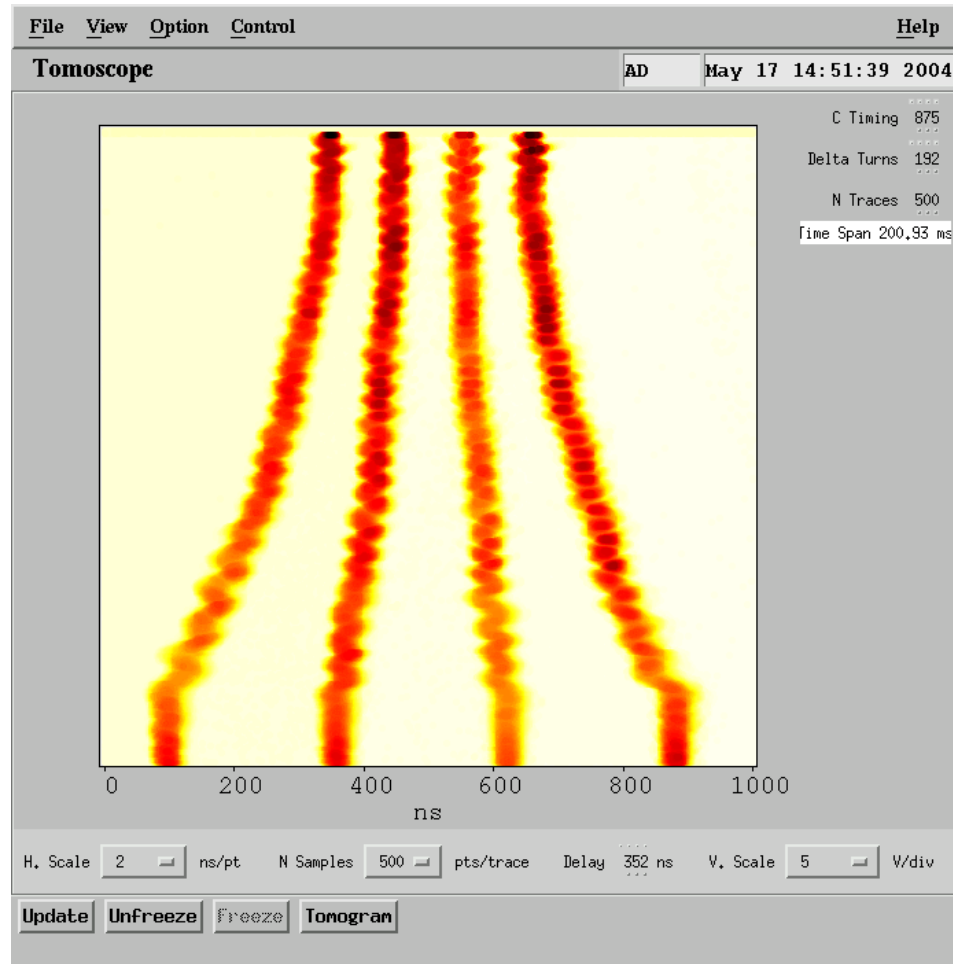
- Bunch splitting or recombination
- One RF frequency is gradually decrease while the other one is increased
- Batch compression

For all these cases the gate generator must be synchronized



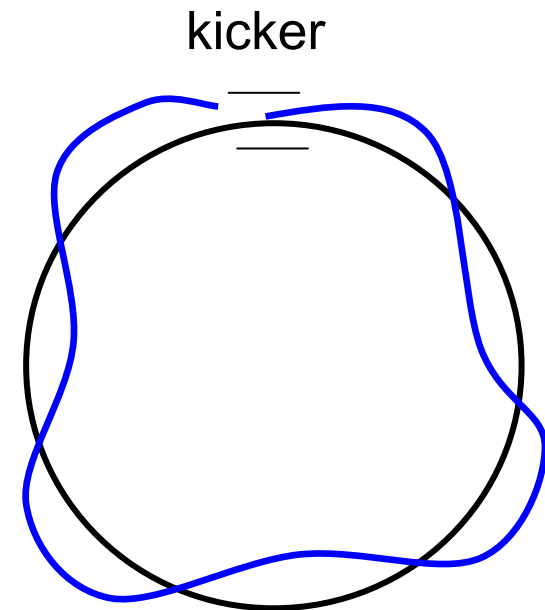


Batch compression

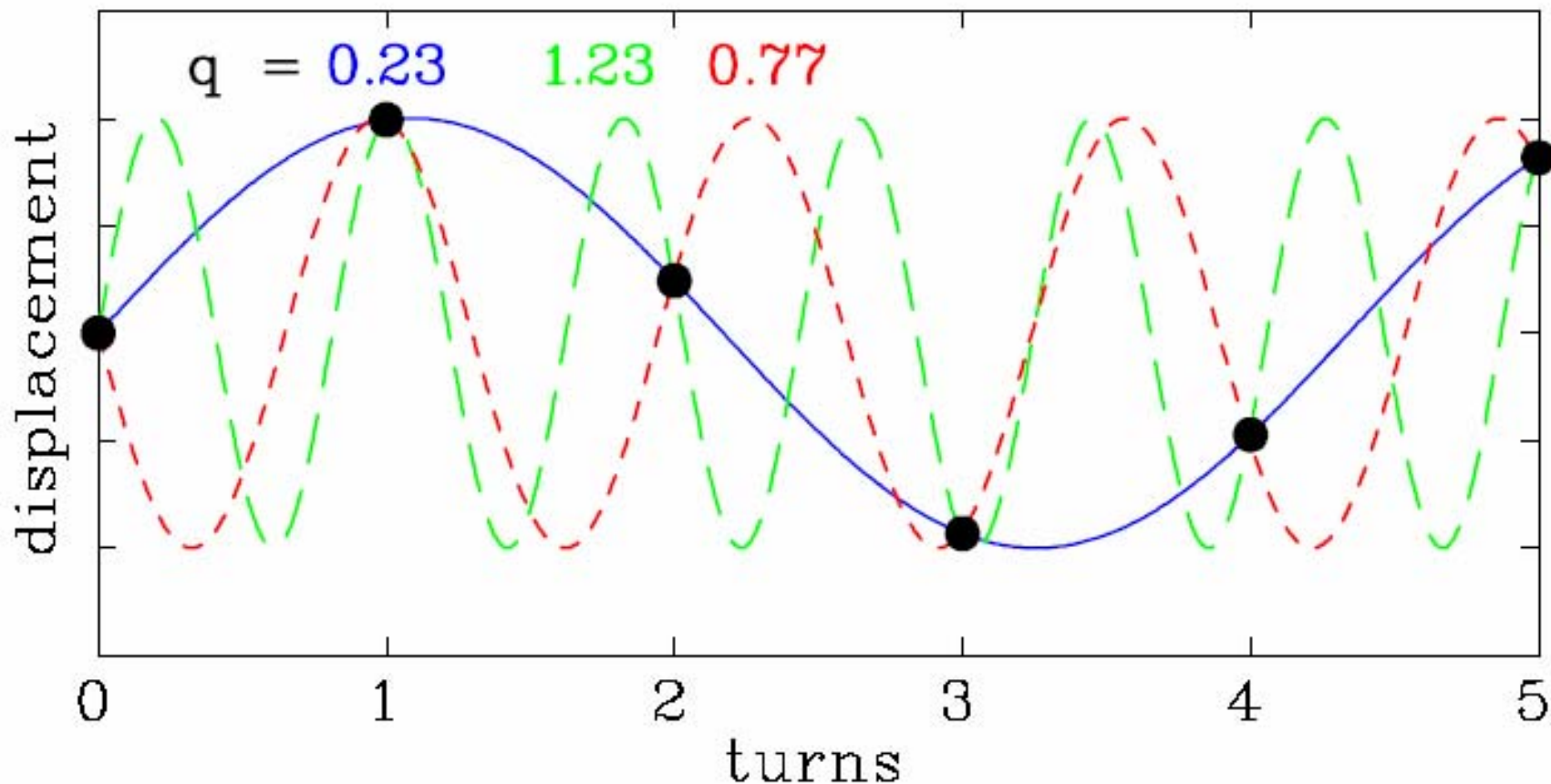


Tune measurements

- When the beam is displaced (e.g. at injection or with a deliberate kick, it starts to oscillate around its nominal orbit (betatron oscillations)
- Measure the trajectory
- Fit a sine curve to it
- Follow it during one revolution

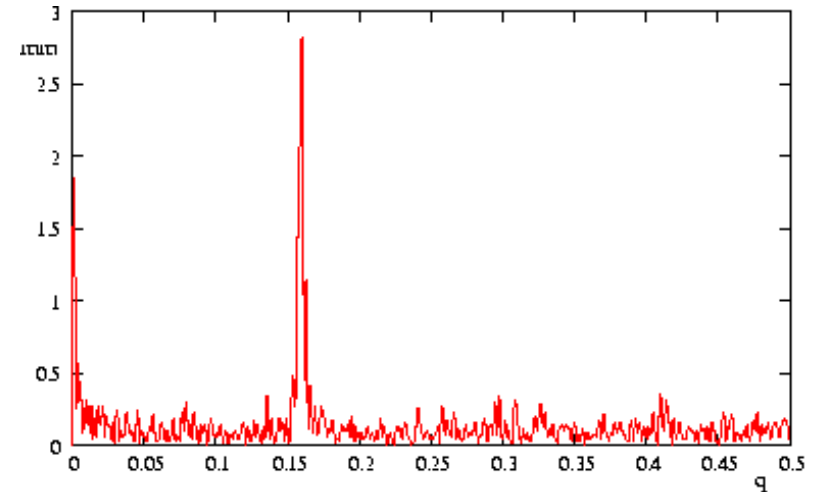
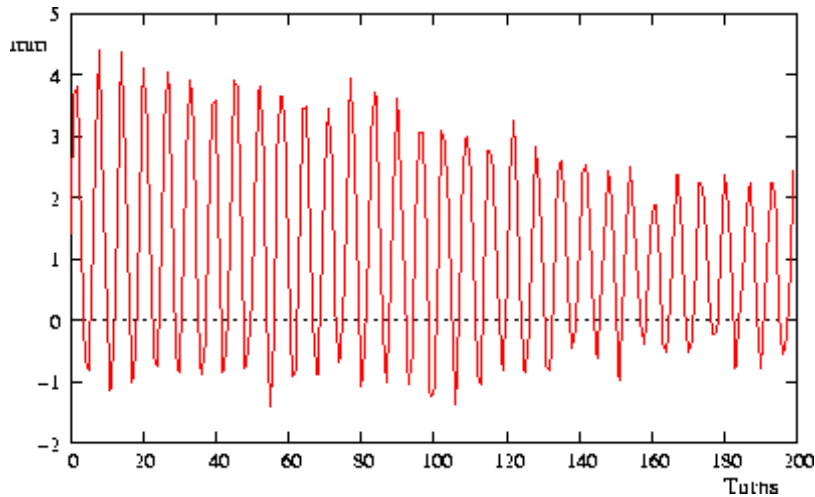


Tune measurements with a single PU



Kicker + 1 pick-up

- Measures only non-integral part of Q
- Measure a beam position at each revolution



Fourier transform of pick-up signal



Further Reading

- P. Forck, **J**oint **U**niversities **A**ccelerator **S**chool (JUAS)
Archamps, France
Course notes: <http://www-bd.gsi.de/conf/juas/juas.html>
- Previous **C**ERN **A**ccelerator **C**ourses
(H. Koziol, Beam Diagnostics Jyväskylä)
- CAS on Beam Measurement 1998 Montreux (Switzerland)
- Proceedings of **D**iagnostics and **I**nstrumentation for **P**article
Accelerators DIPAC (Europe) and **B**eam **I**nstrumentation
Workshop BIW (USA)